LIGO-T050085-00-D

X-IronPort-AV: i="3.93,115,1114956000";

d="opd'?gif'147?scan'147,208,147"; a="38070023:sNHT1061221100"

Subject: RE: 4ITM01

Date: Wed, 18 May 2005 11:37:27 +1000

X-MS-Has-Attach: yes X-MS-TNEF-Correlator: Thread-Topic: 4ITM01

Thread-Index: AcVX0Ze60oyJx7S9R0iy312qDoU9fQDdmlhq

From: <Bob.Oreb@csiro.au>
To: <gari@ligo.caltech.edu>
Cc: <ahelena@ligo.caltech.edu>

X-OriginalArrivalTime: 18 May 2005 01:37:28.0467 (UTC) FILETIME=[26AF7E30:01C55B4A]

X-Spam-Score: undef - Domain Whitelisted (csiro.au:)

X-Scanned-By: Canlt (www . roaringpenguin . com) on 131.215.115.14

Dear Gari

We have cleaned both sides of the 4ITM01 and carried out a quick measurement of the surface figure on the LADI. The attached files show the "opd" maps for both sides with Power and Tilt removed while the "gif" files show profile plots along the two opd phase maps. You can see that side 2 looks fairly good and clean however side 1 is full of streaks and artefacts which were not there initially when we delivered the optic to you. The streaks have significant surface relief (all appear positive relief)as you can see in the corresponding gif file for side 1 (typically the peak relief is ~ 4 nm to ~ 8 nm for the streaks and much larger for the two red coloured artefacts or areas). I am not sure what value TOPO measurements will be and at which locations we should do the TOPO measurements. If you still want us to do the TOPO measurements then perhaps you can indicate which specific areas of the phase map you want us to concentrate on.

Regards

Bob

----Original Message-----

From: gari@ligo.caltech.edu [mailto:gari@ligo.caltech.edu]

Sent: Saturday, 14 May 2005 2:35 AM

To: Oreb, Bob (CIP, Lindfield)
Cc: Billingsley_G@ligo.caltech.edu

Subject: RE: 4ITM01

Hi Bob,

I'm glad you have made it back home safely, I hope the trip went well? By all means, please do clean 4ITM01. It certainly has sat around here for a while. Our interest lies in how the surface has changed since the

piece left CSIRO lo, those many years ago! Specifically TOPO measurements at the locations that the phase maps show the streaks, and also where measured as a part of your initial certification.

It was really great to see all of you, I'm so sorry I couldn't join you for lunch.
Cheers,
GariLynn

>To: <Billingsley_G@ligo.caltech.edu>

>Cc: <ahelena@ligo.caltech.edu>, <Jeff.Seckold@csiro.au>

>Subject: RE: 4ITM01

>Dear Gari

- Doai

>Firstly thank you and Helena very much for the wonderful reception you

>gave us during our recent visit to Caltech including the delicious lunch

>at the beautiful Athenaeum. I am always impressed with the beauty of the

>campus and Pasadena in general.

>We have received the 4ITM01 substrate and had a bit of an inspection of

>the two surfaces. I am told by Jeff that the surfaces are surprisingly >dirty (possibly due to handling and exposure to unclean environment)

>that doing TOPO measurements on the surfaces as is (without cleaning) >will possibly be meaningless and a waste of time. I didn't want our guys

>to do any cleaning of the surfaces prior to obtaining your instructions.

>If you think that some useful data can be obtained before cleaning the >surfaces we can do a set of TOPO measurements prior to any cleaning and

>if you like we can then clean the surfaces and remeasure. Please let me

>know how you want us to proceed.

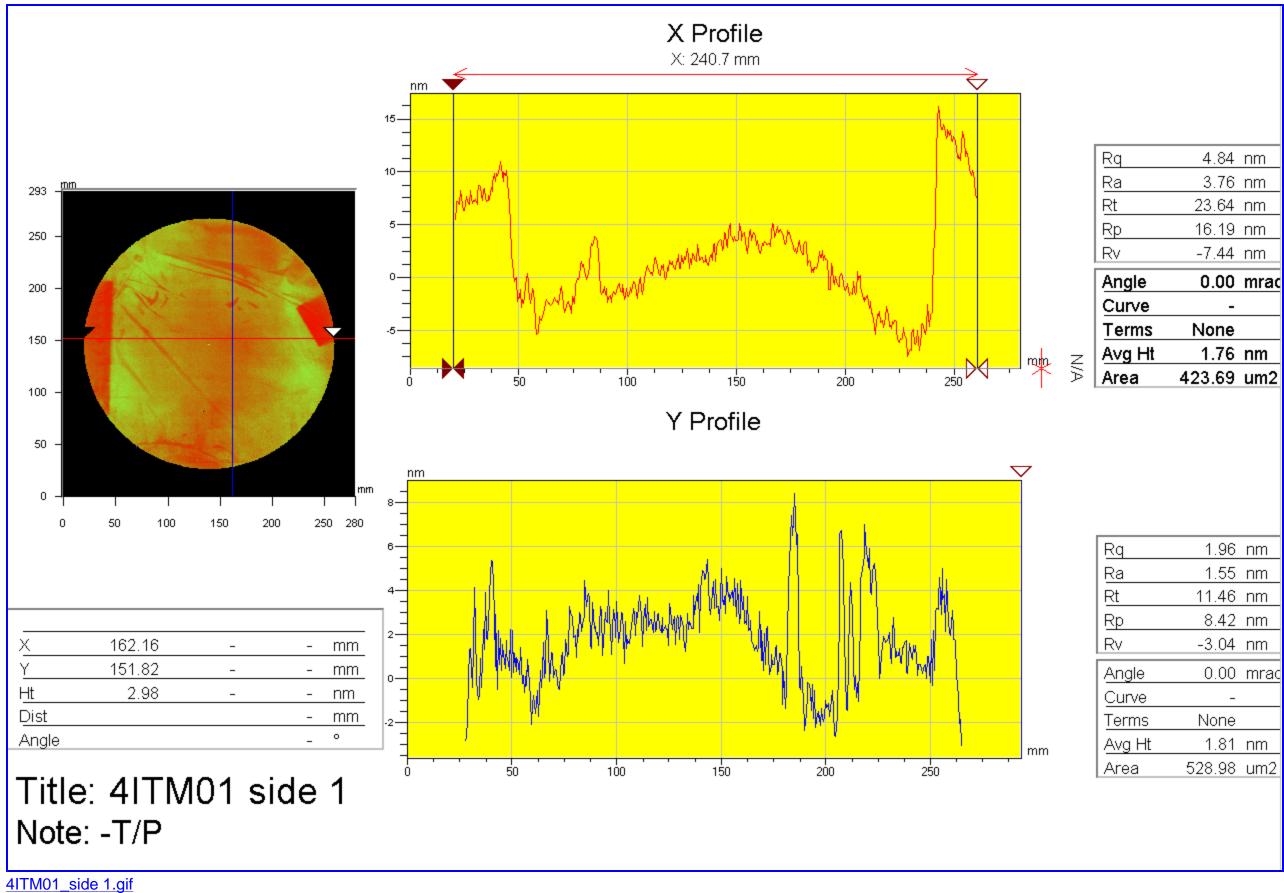
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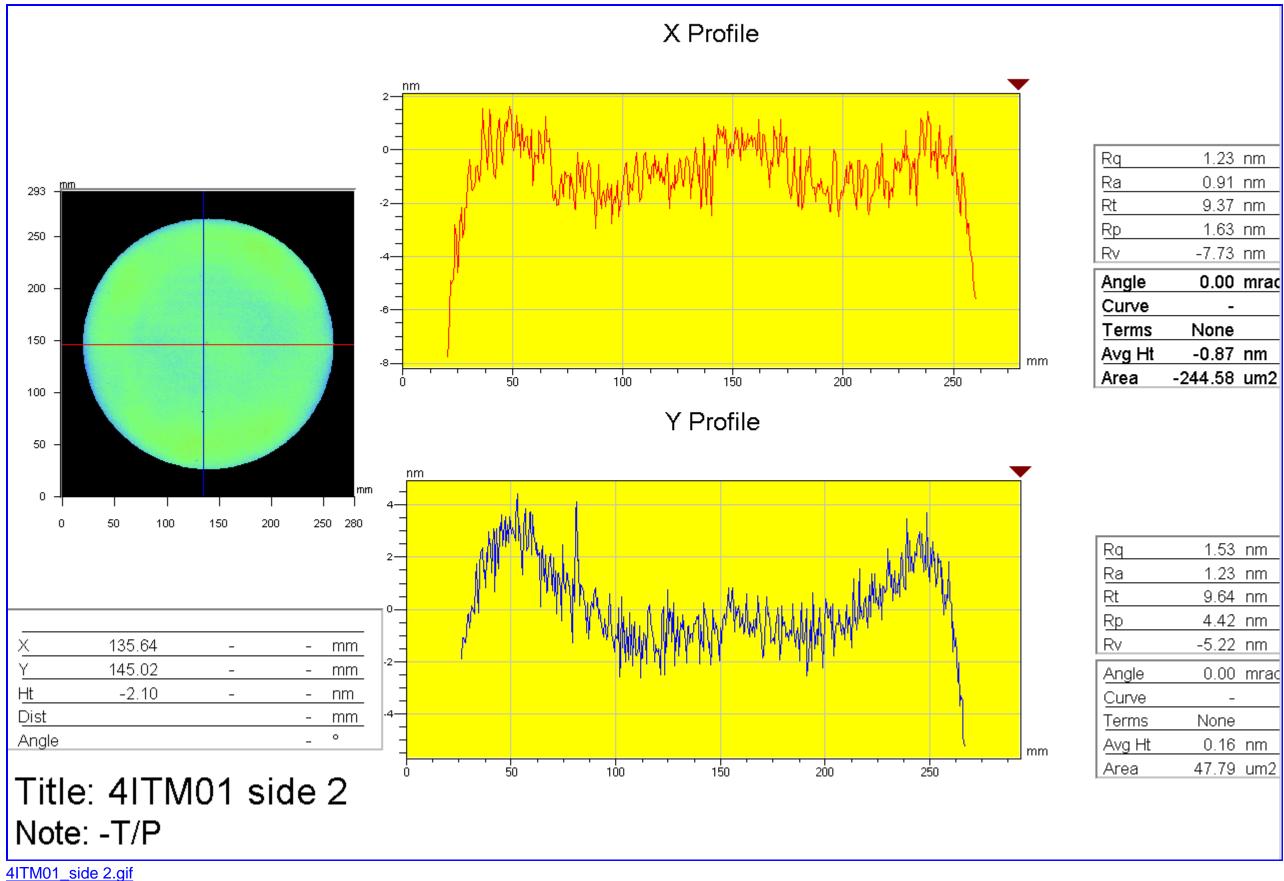
>Regards

>

>Bob

Printed for GariLynn Billingsley <Billingsley_G@ligo.caltech.edu>





X-IronPort-AV: i="3.93,130,1114956000";

d="gif'147?scan'147,208,147"; a="38915352:sNHT580522330"

Subject: RE: 4ITM01

Date: Tue, 24 May 2005 18:22:23 +1000

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Thread-Index: AcVb0S8MAwFJSjSiTpiL5gfxTVDvZgEaC63g

From: <Bob.Oreb@csiro.au>
To: <gari@ligo.caltech.edu>

X-OriginalArrivalTime: 24 May 2005 08:22:23.0594 (UTC) FILETIME=[B6302CA0:01C56039]

X-Spam-Score: undef - Domain Whitelisted (csiro.au:)

X-Scanned-By: Canlt (www . roaringpenguin . com) on 131.215.115.14

Gari

Please find attached the gif files for the TOPO measurements of Side 1 of 4ITM01 on 2.5X magnification. The X40 magnification data will follow in a separate email.

Bob

----Original Message-----

From: gari@ligo.caltech.edu [mailto:gari@ligo.caltech.edu]

Sent: Thursday, 19 May 2005 4:44 AM To: Oreb, Bob (CIP, Lindfield)

Subject: RE: 4ITM01

Bob,

Yes, these are the same streaks that we have seen. Due to our limited aperture though, we have not seen the linear (square) features at the edges. I assume these are real and not any part of your measurement or cleaning method.

The reason the TOPO measurements are important to us is that we want to determine if it is this process that also causes the excess scatter we see in the interferometers.

Currently we see about 60ppm per mirror of loss due to scatter. This is

far beyond what we would expect from microroughness and defects alone. We have confirmed that the loss is high on our coated optics, even after

cleaning, so we don't think it is a contamination issue.

Our suspicion is that the liquinox cleaning (done before coating) not only leaves these streaks, but may also spoil the microroughness. So we do want to measure the part on the TOPO at the same locations that

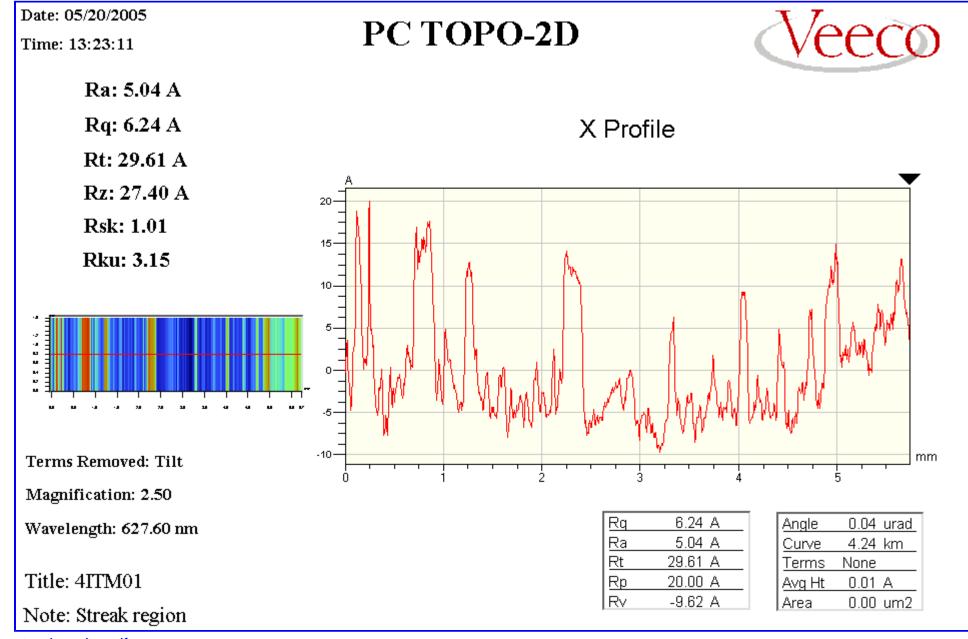
were initially certified, so that we have a direct comparison of

microroughness.

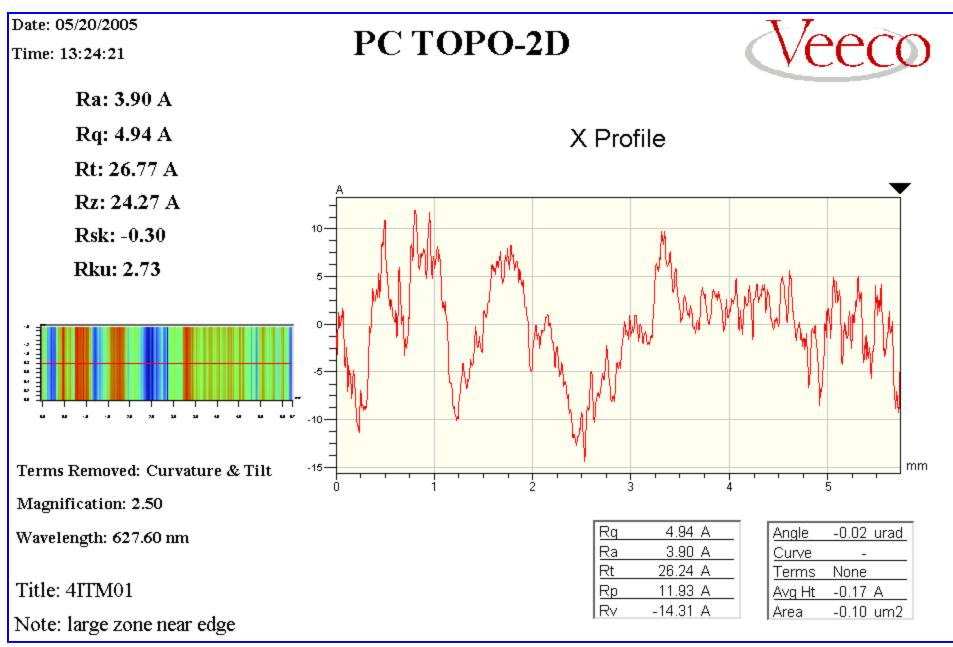
We're also interested in the microroughness on a streaky (raised) area.

Perhaps the original surface roughness remains in these areas?

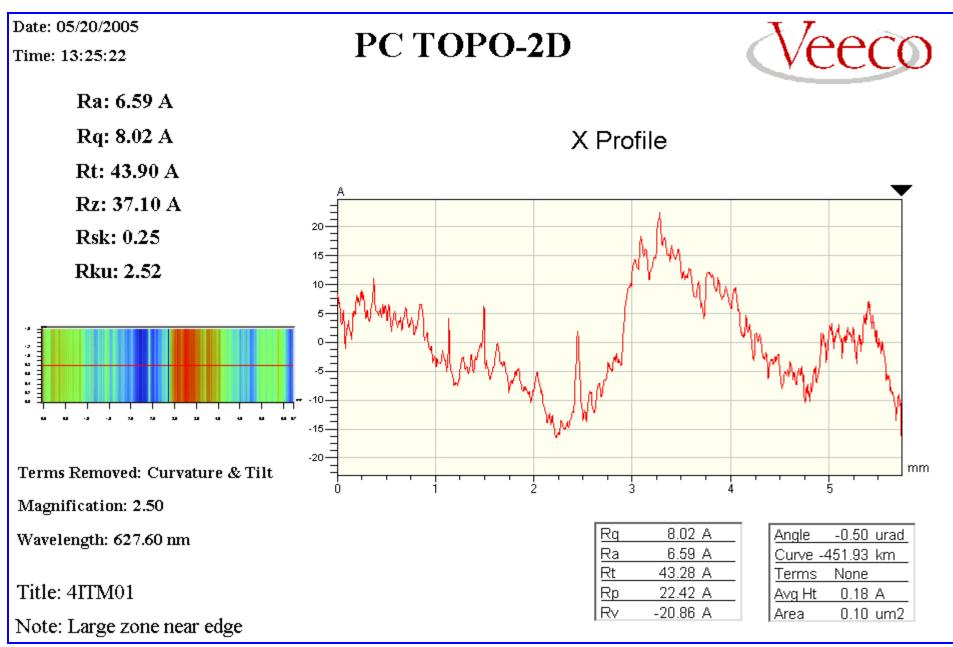
Cheers, Gari



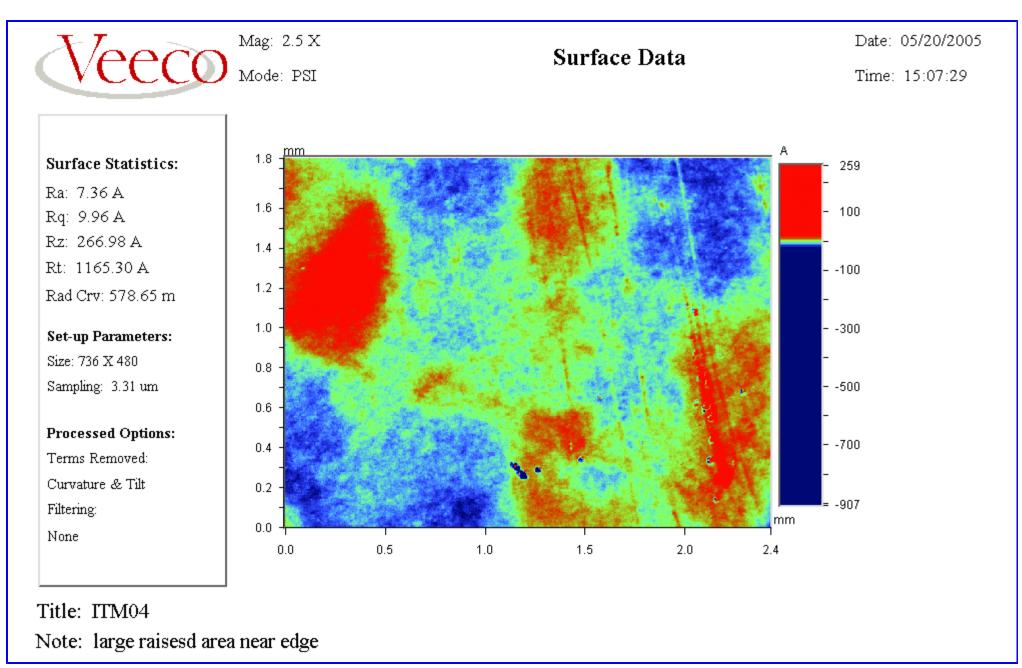
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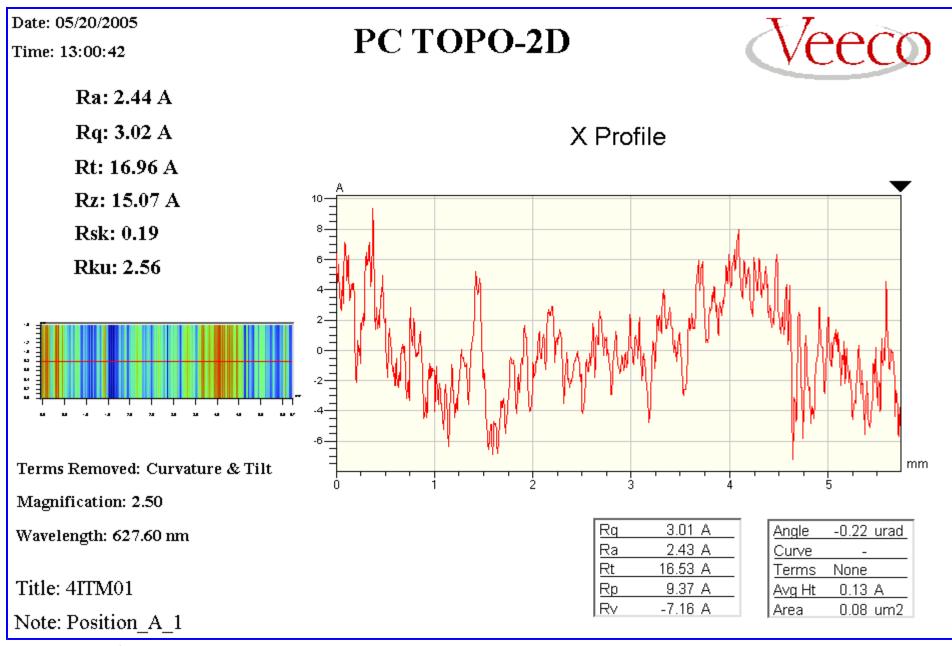
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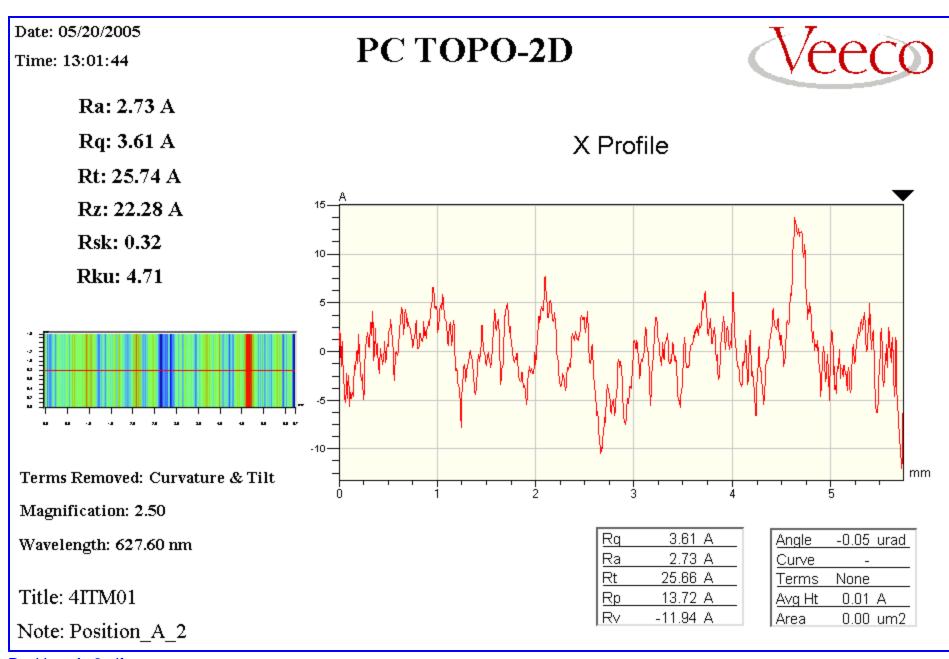
large zone near edge_2.gif



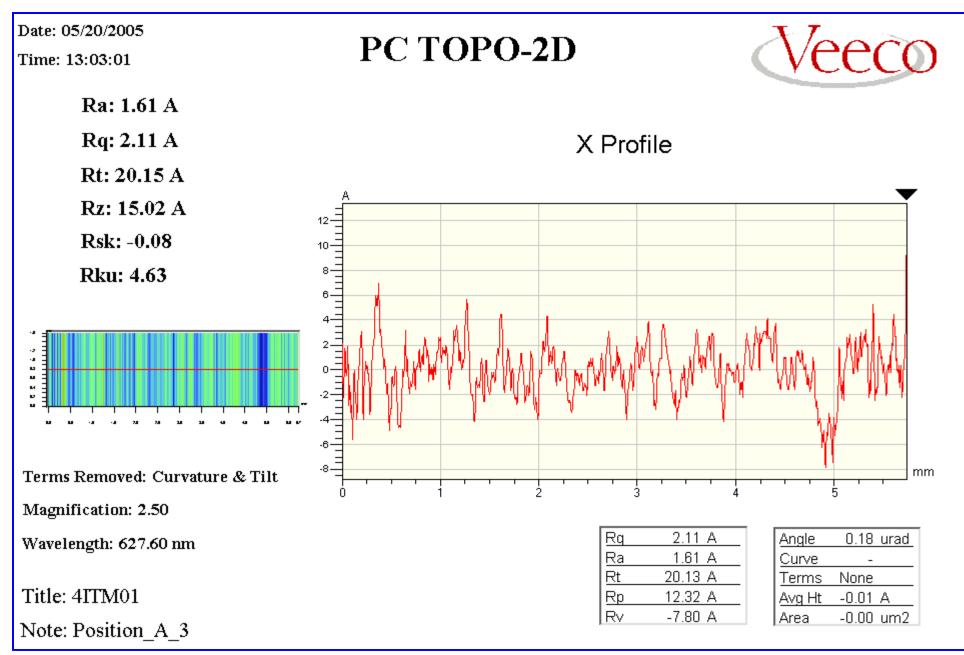
large zone near edge_3D.gif



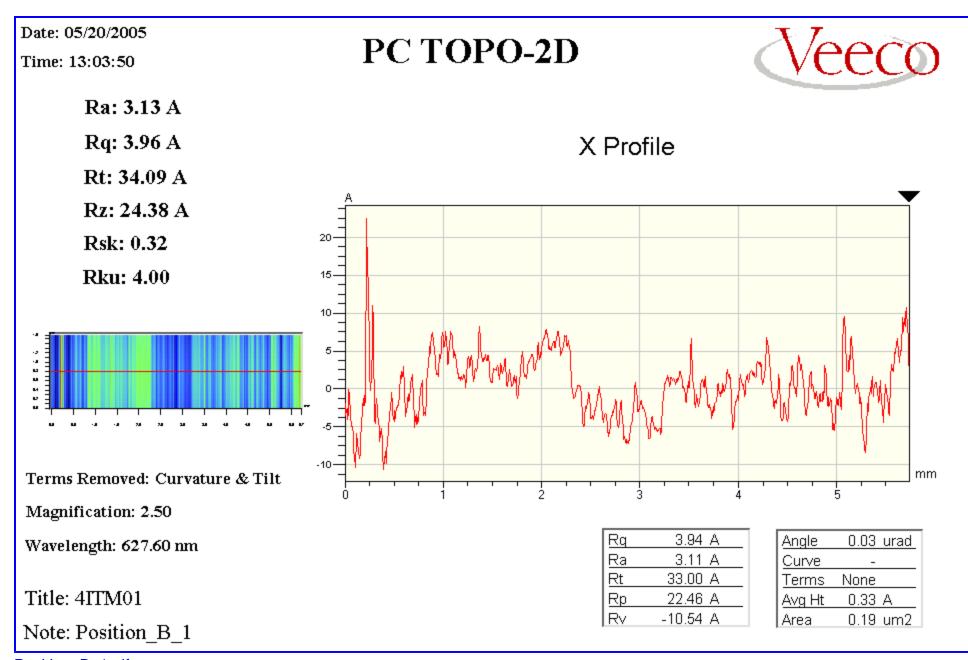
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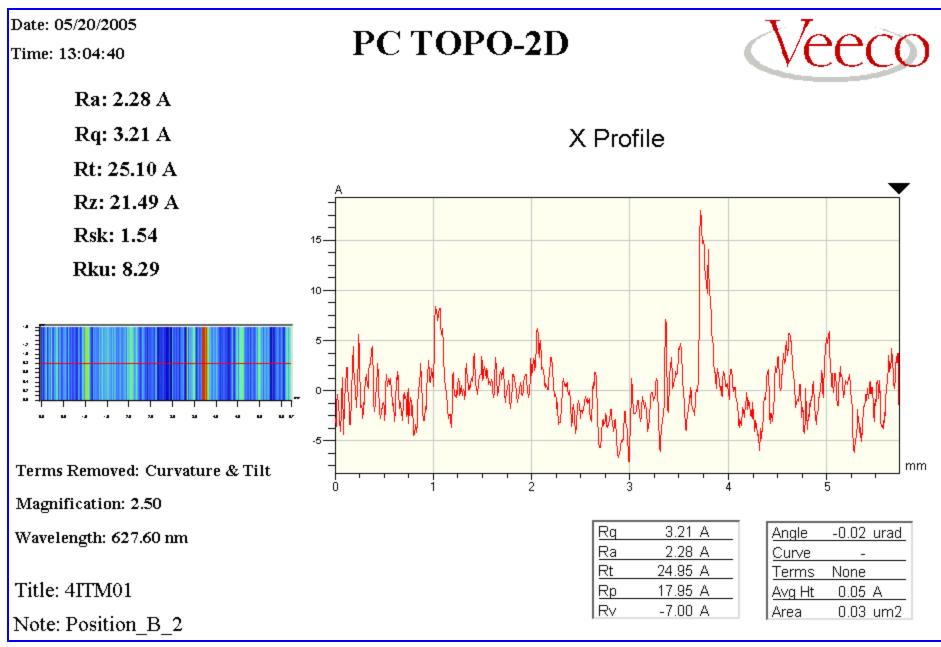
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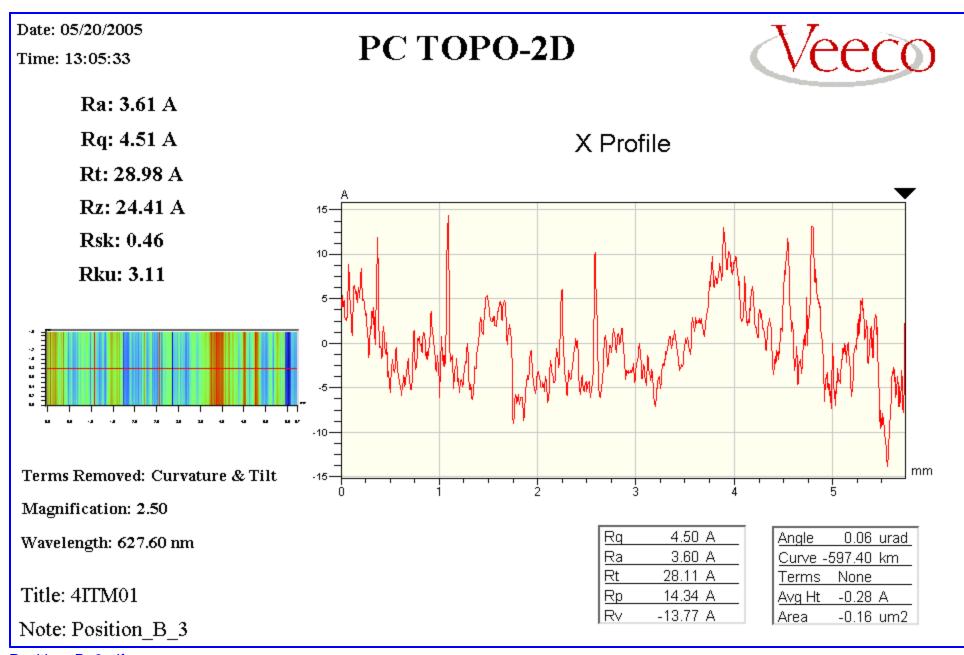
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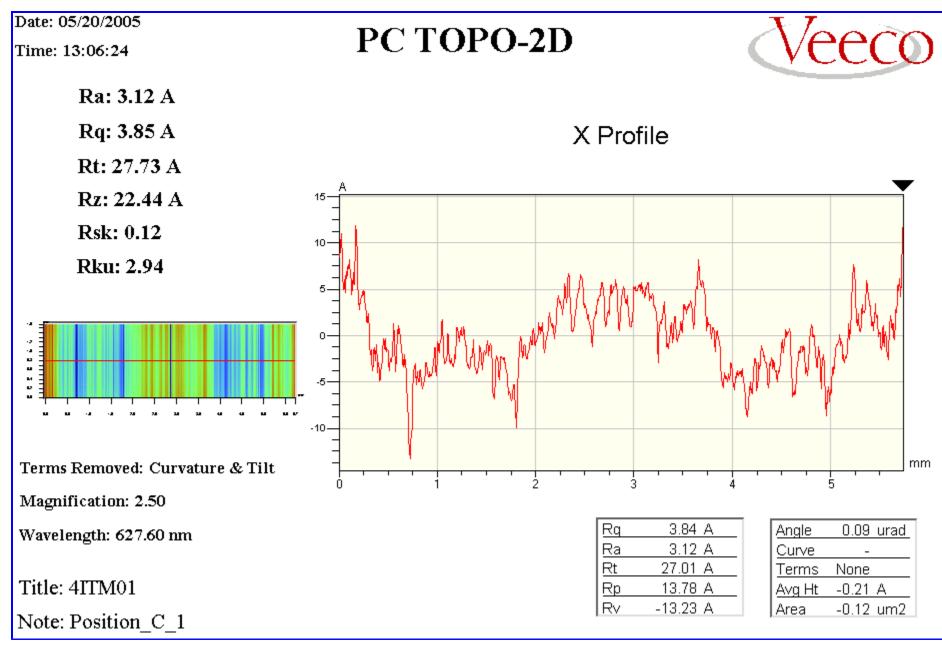
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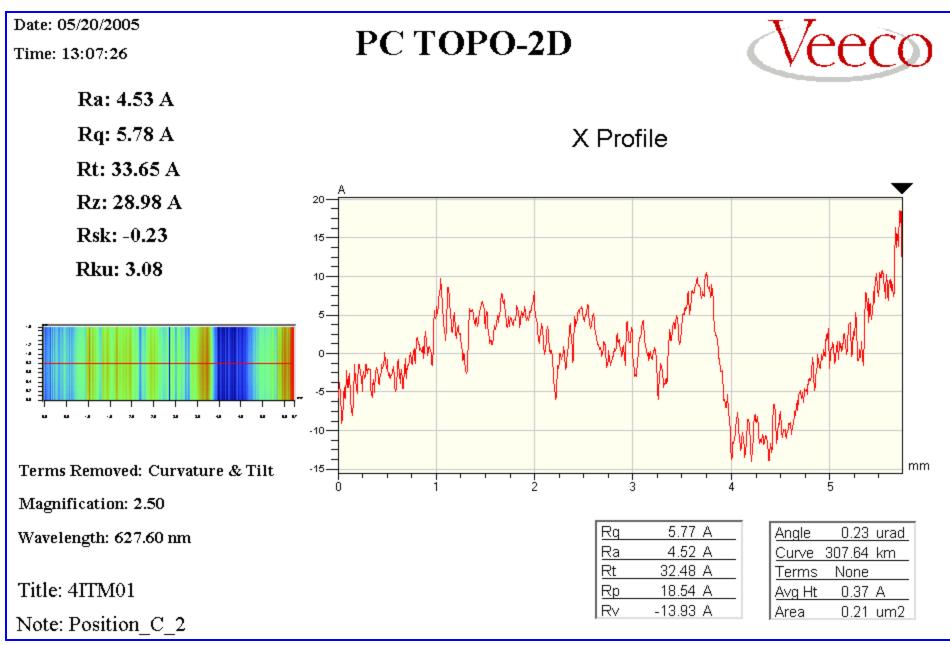
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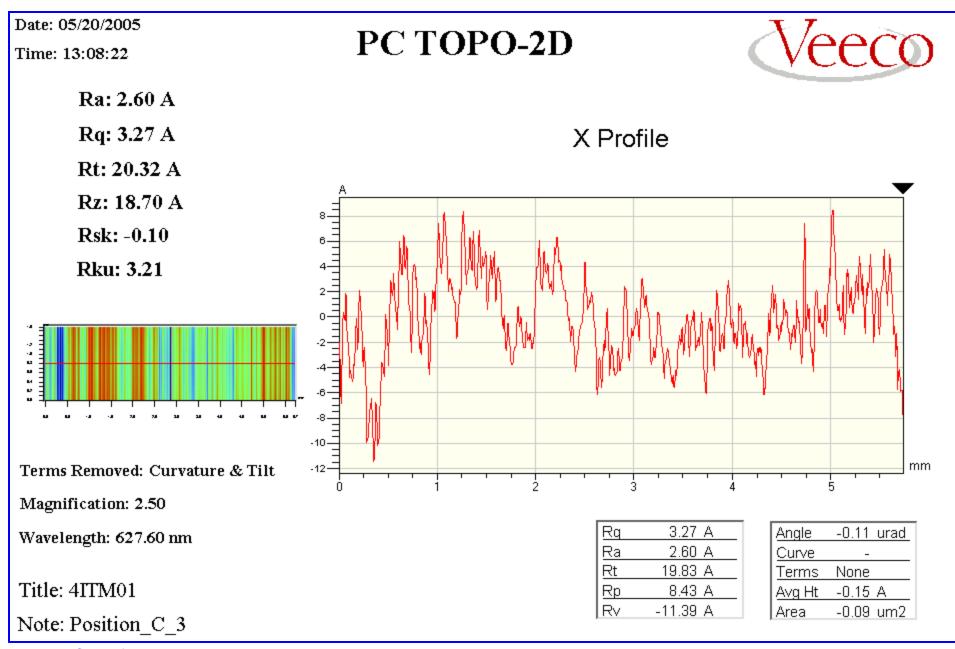
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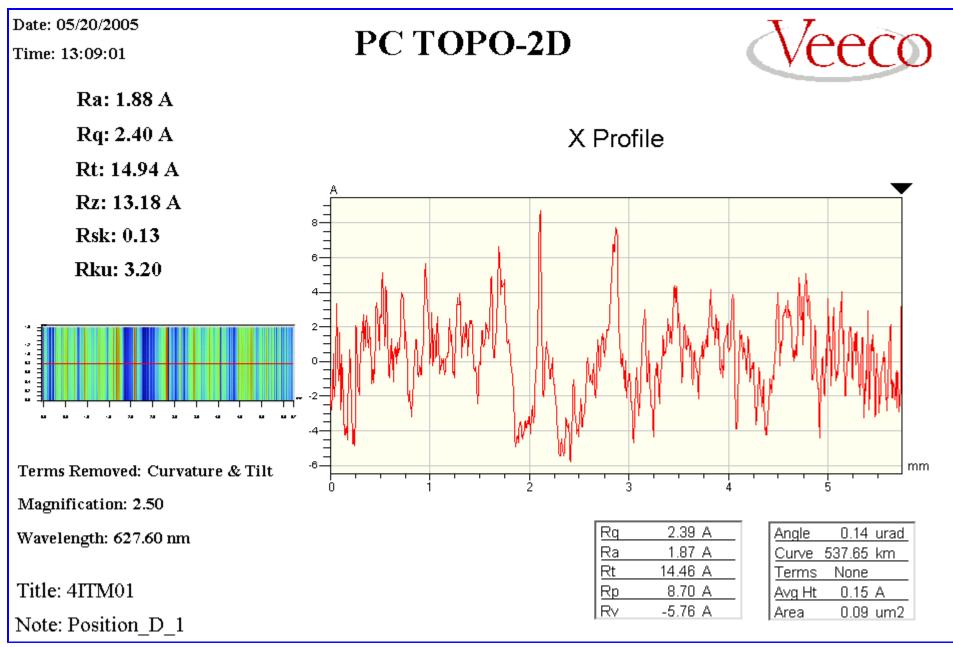
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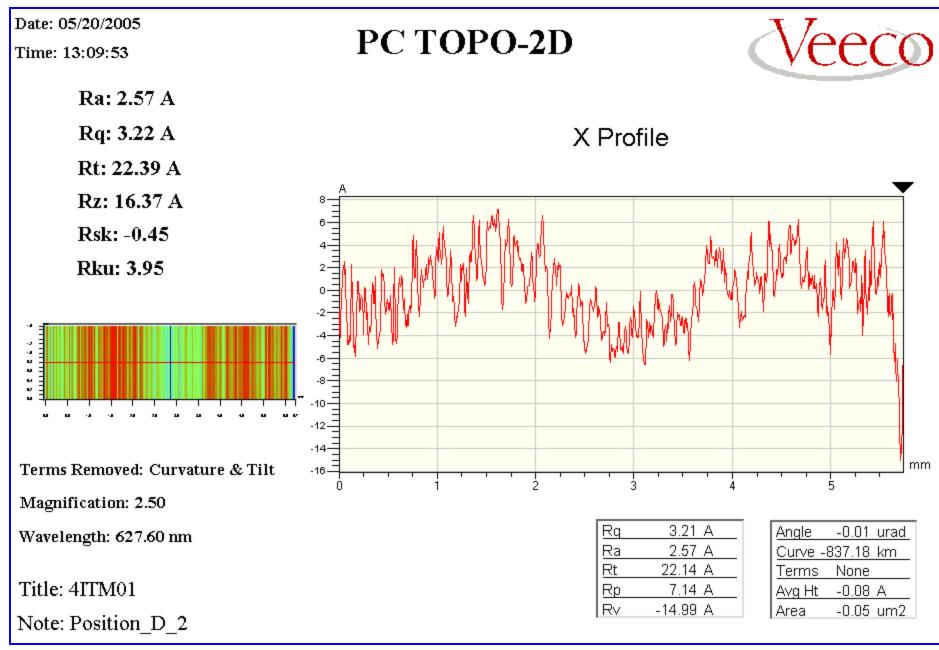
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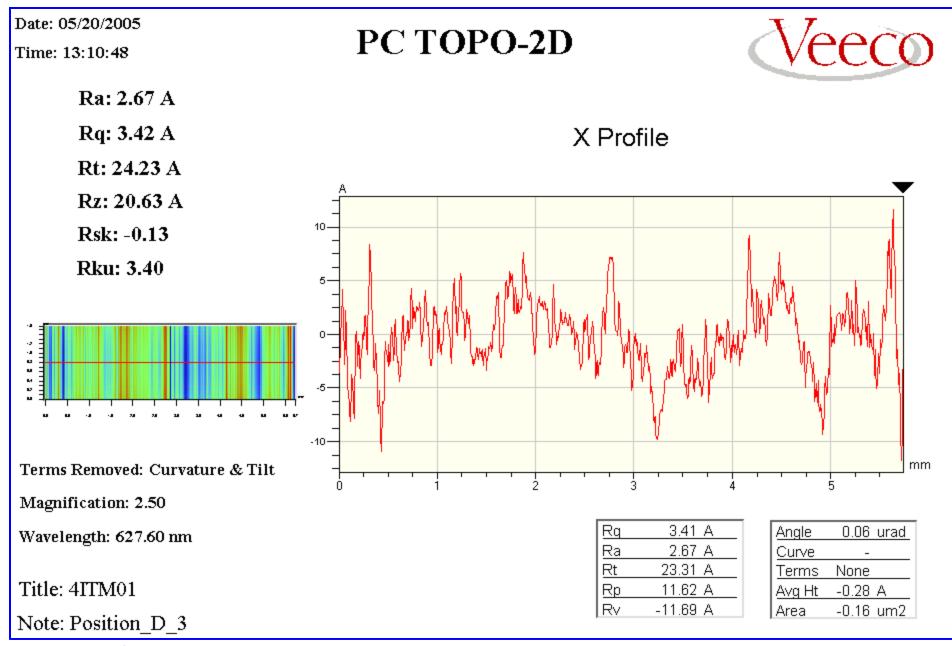
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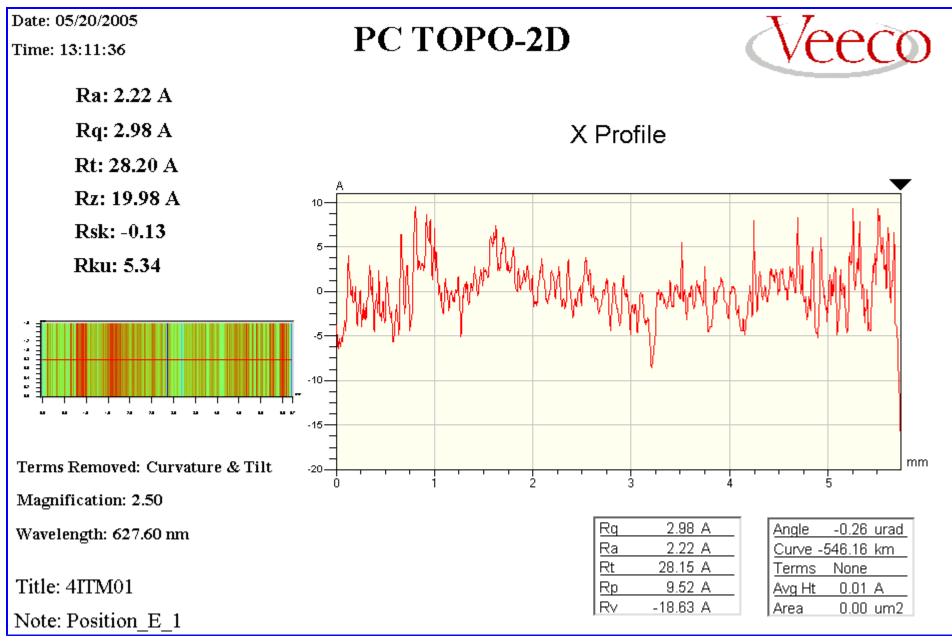
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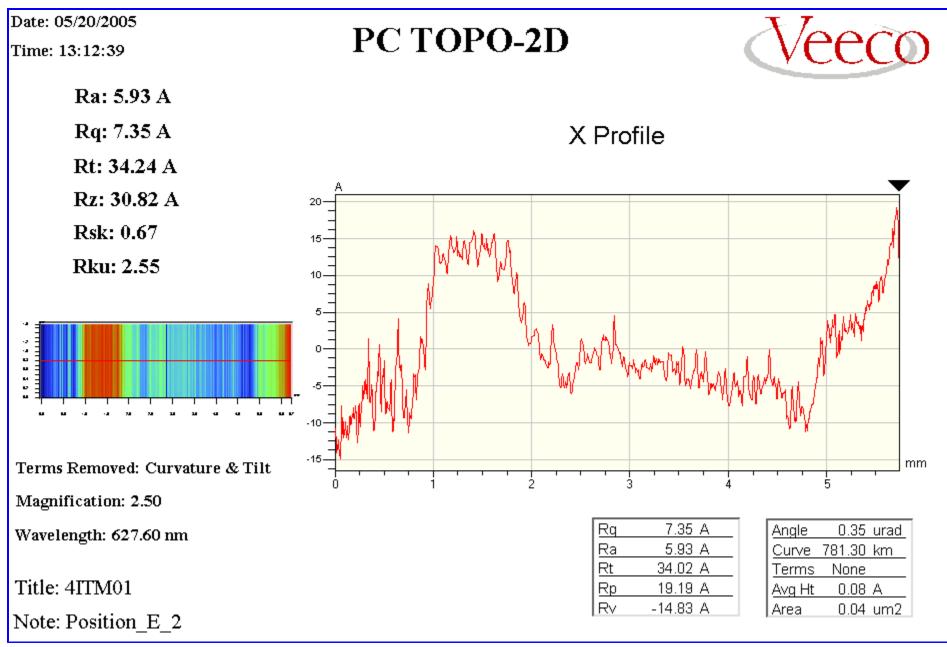
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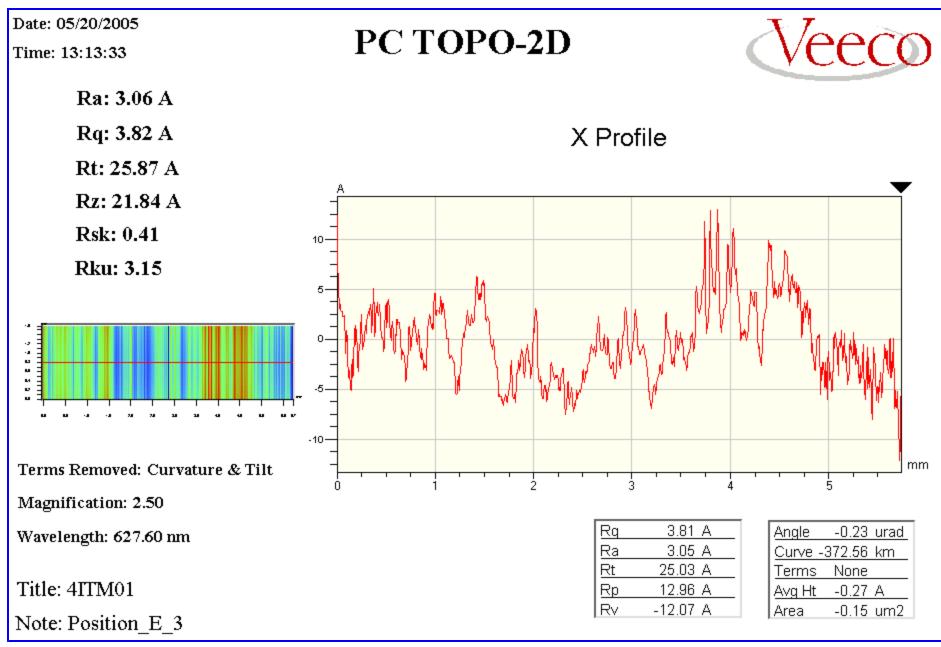
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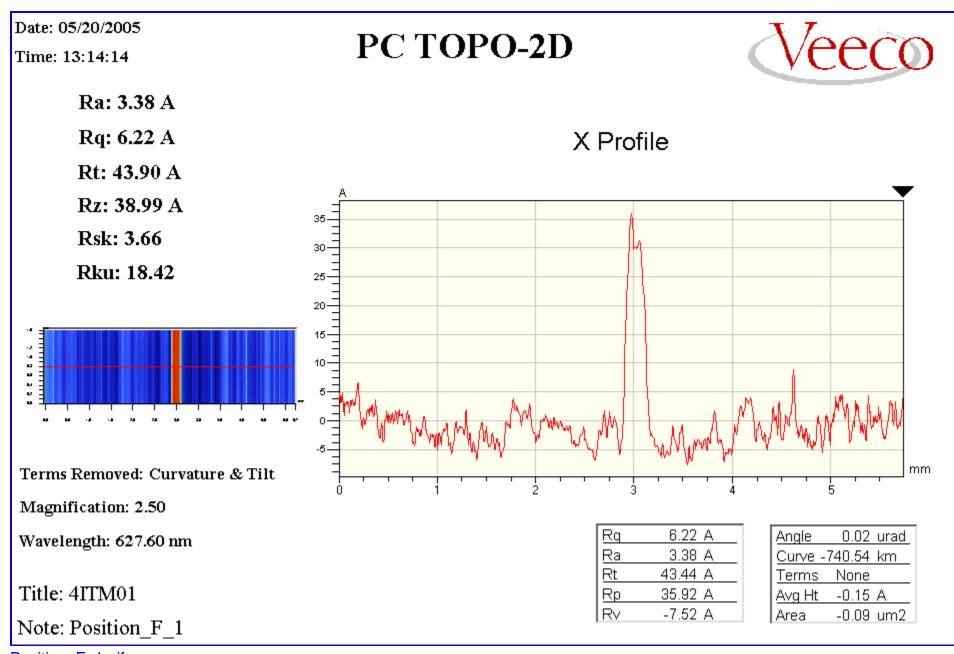
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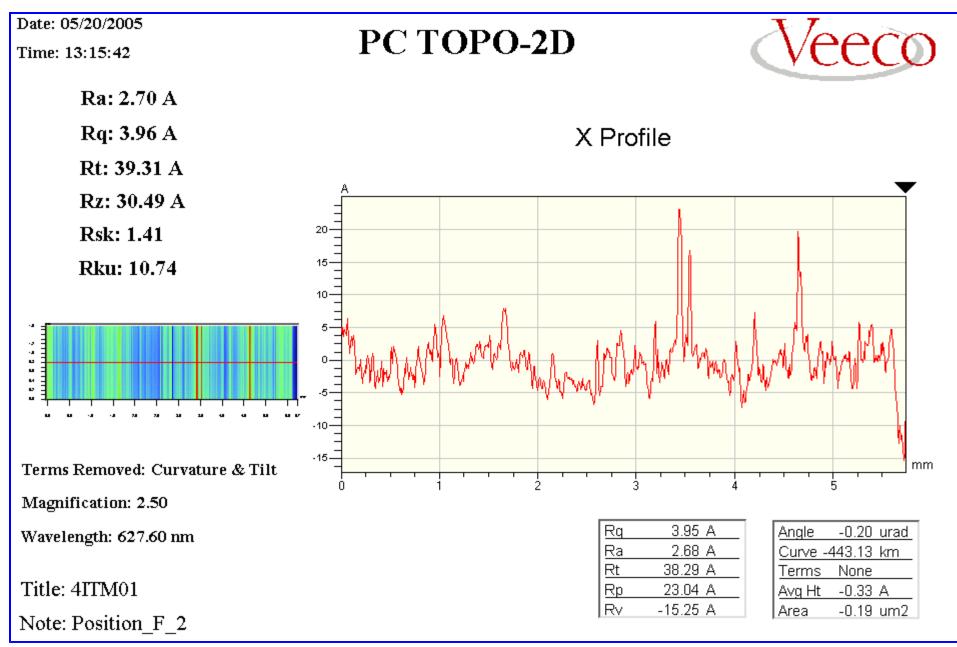
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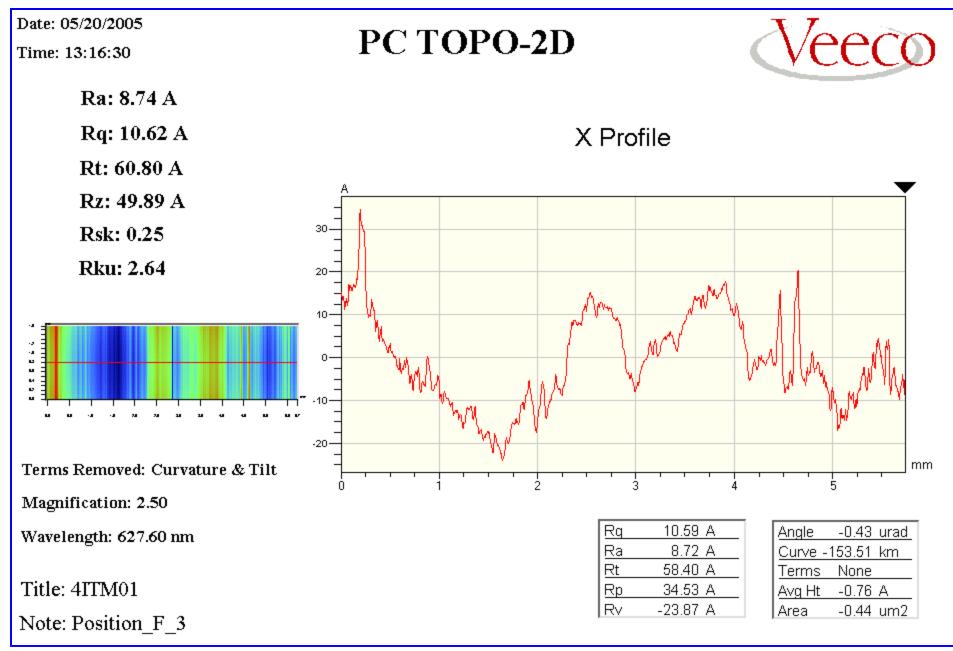
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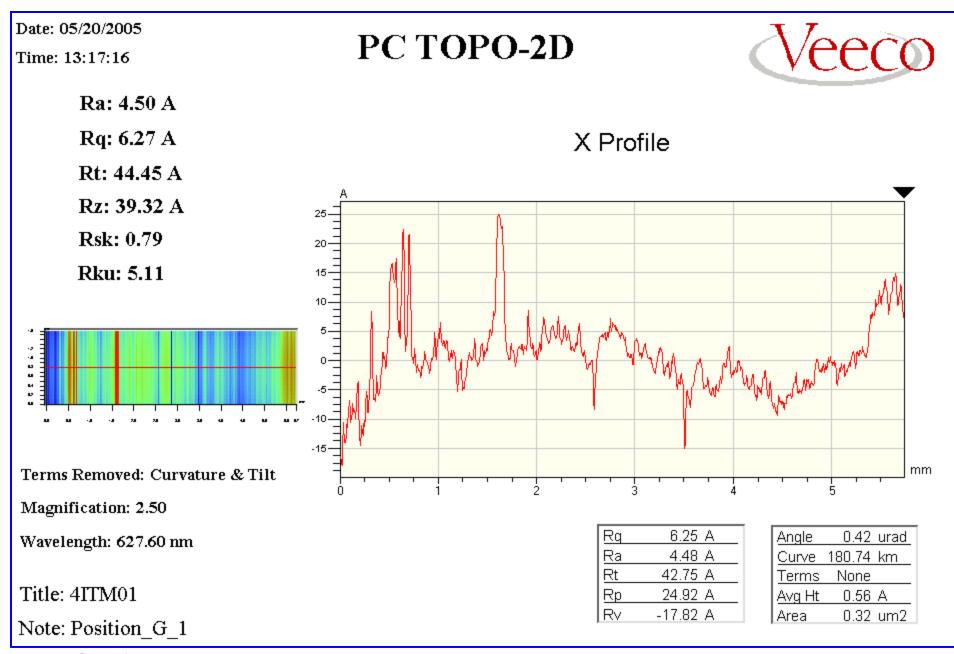
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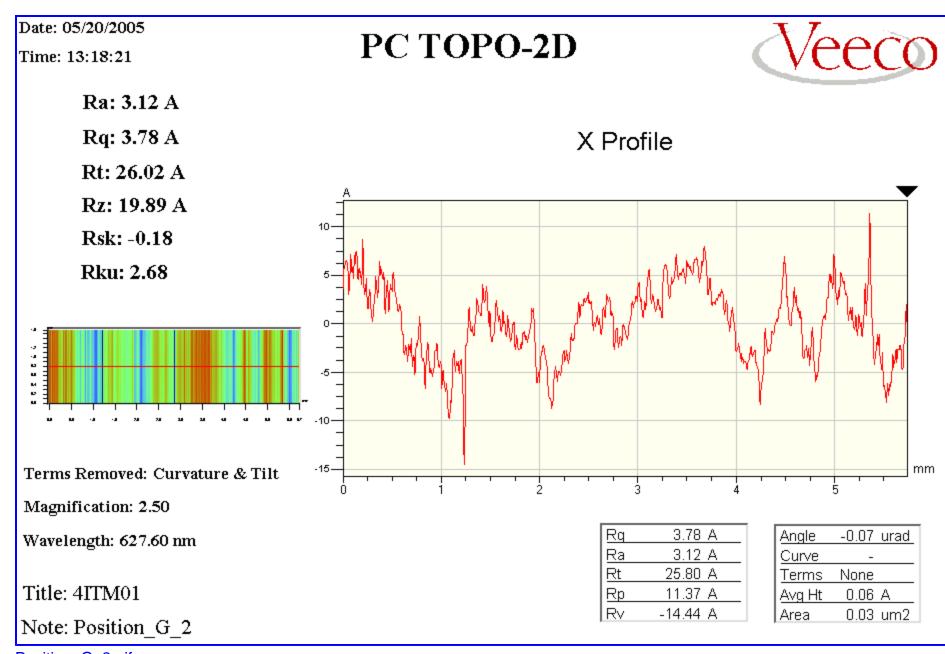
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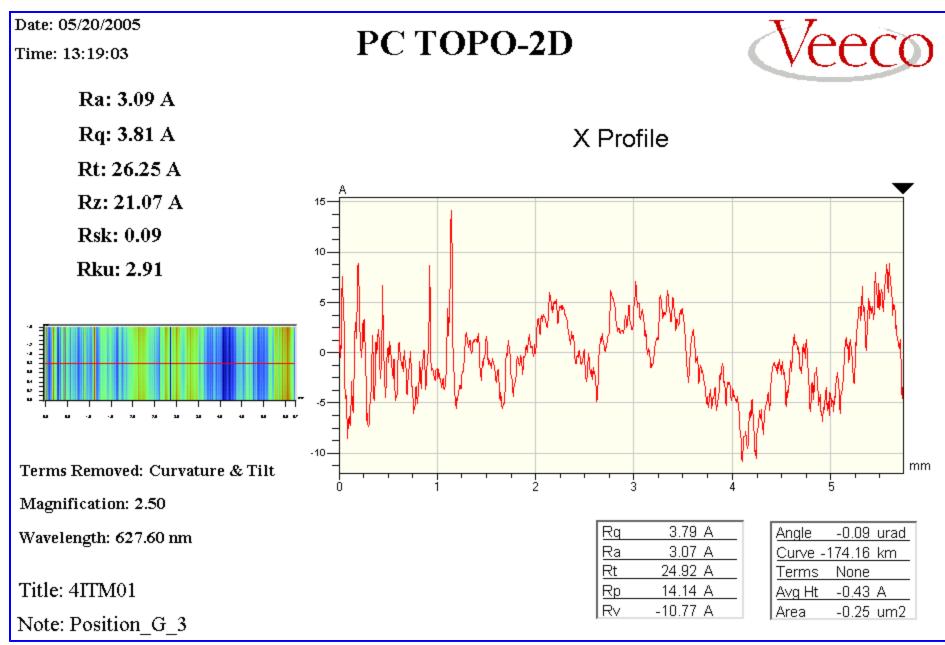
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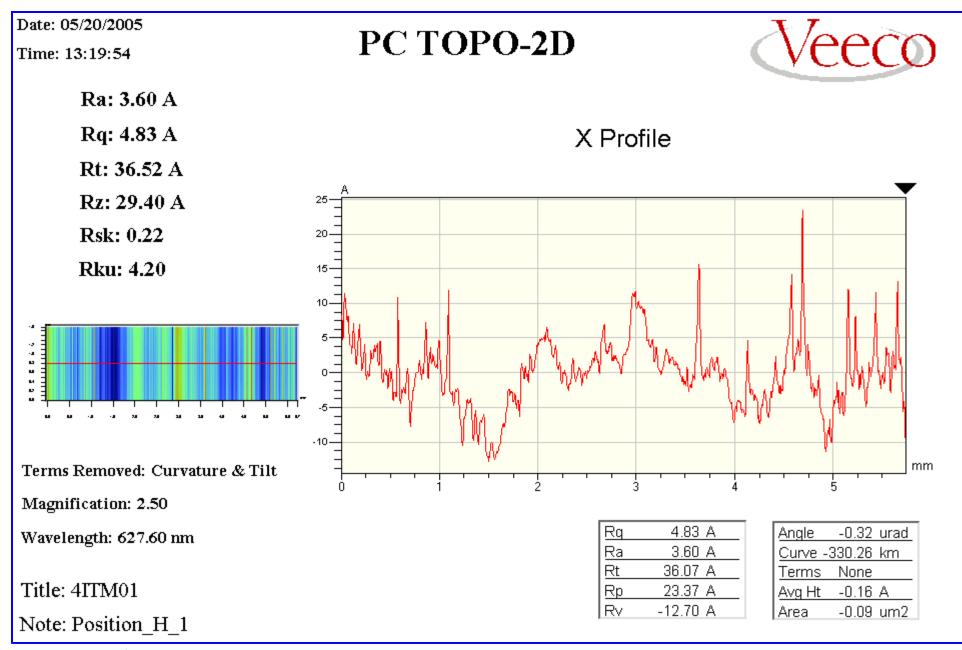
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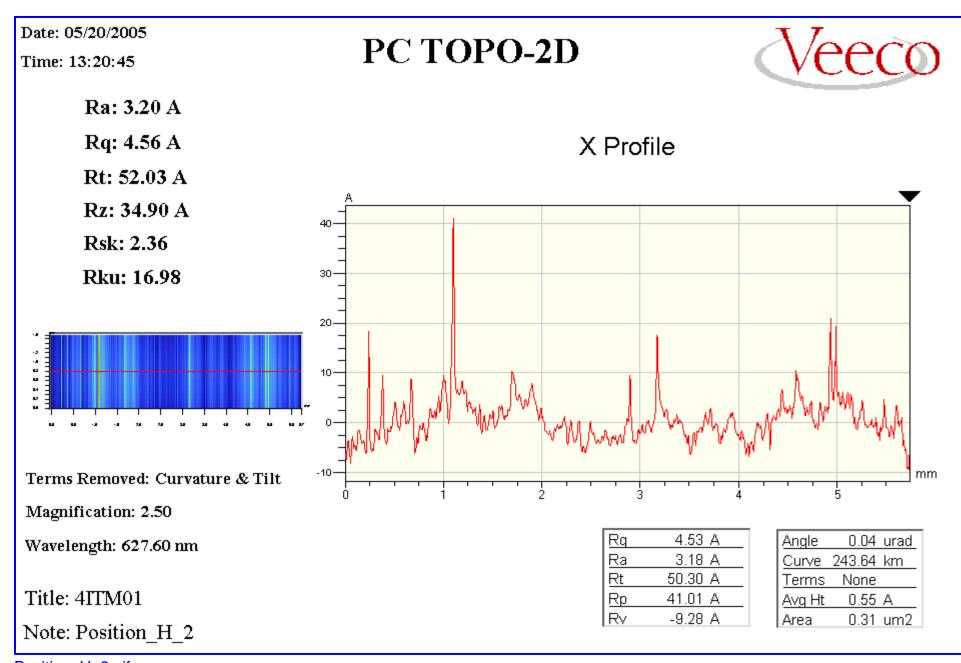
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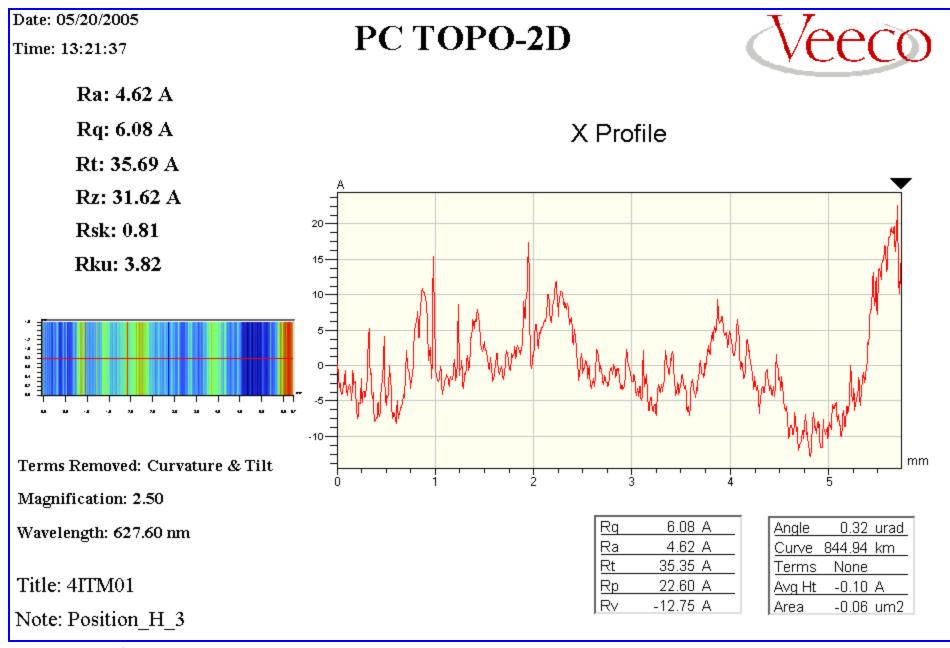
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Position_H_2.gif



Position_H_3.gif

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Subject: RE: 4ITM01

Date: Tue, 24 May 2005 18:24:20 +1000

X-MS-Has-Attach: yes X-MS-TNEF-Correlator: Thread-Topic: 4ITM01

Thread-Index: AcVb0S8MAwFJSjSiTpiL5gfxTVDvZgEaKCEw

From: <Bob.Oreb@csiro.au> To: <gari@ligo.caltech.edu>

X-OriginalArrivalTime: 24 May 2005 08:24:20.0717 (UTC) FILETIME=[FBFFB9D0:01C56039]

X-Spam-Score: undef - Domain Whitelisted (csiro.au:)

X-Scanned-By: Canlt (www . roaringpenguin . com) on 131.215.115.14

Gari

Please find attached the gif files for the TOPO measurements of Side 1 of 4ITM01 on 40X magnification.

Bob

-----Original Message-----

From: gari@ligo.caltech.edu [mailto:gari@ligo.caltech.edu]

Sent: Thursday, 19 May 2005 4:44 AM

To: Oreb, Bob (CIP, Lindfield)

Subject: RE: 4ITM01

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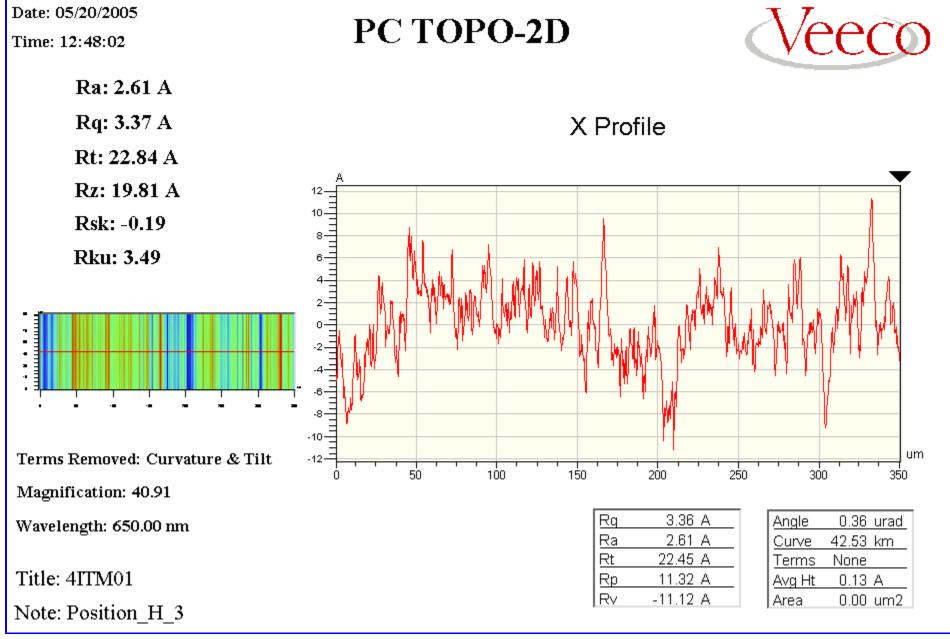
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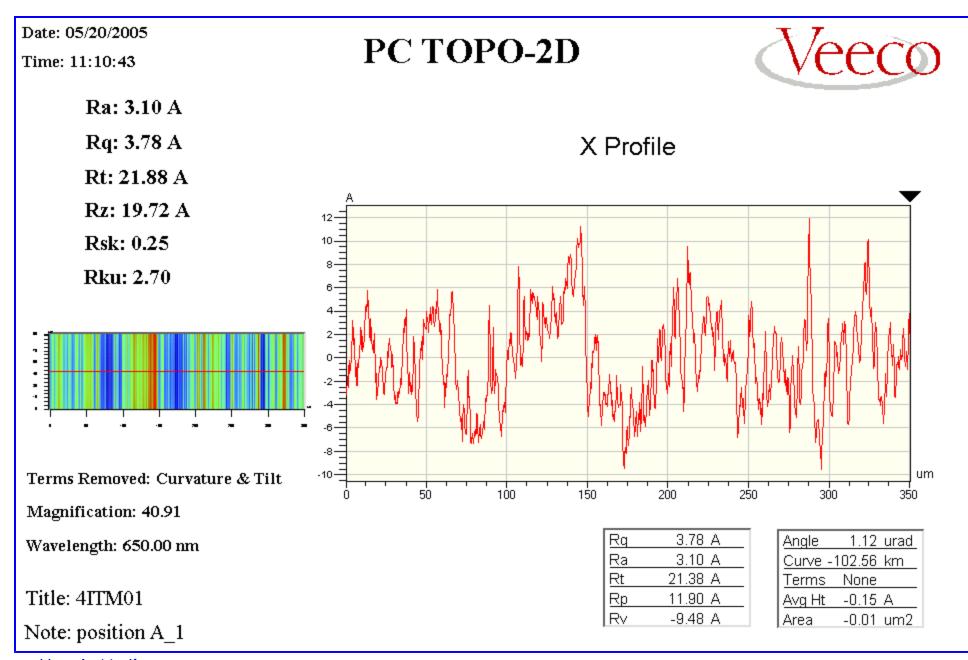
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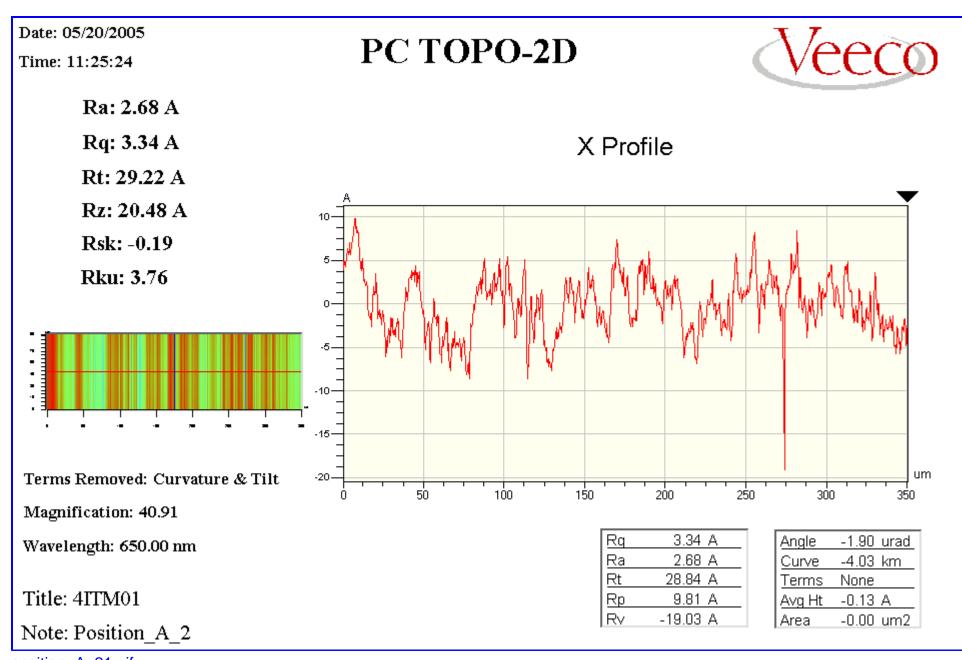
Cheers, Gari



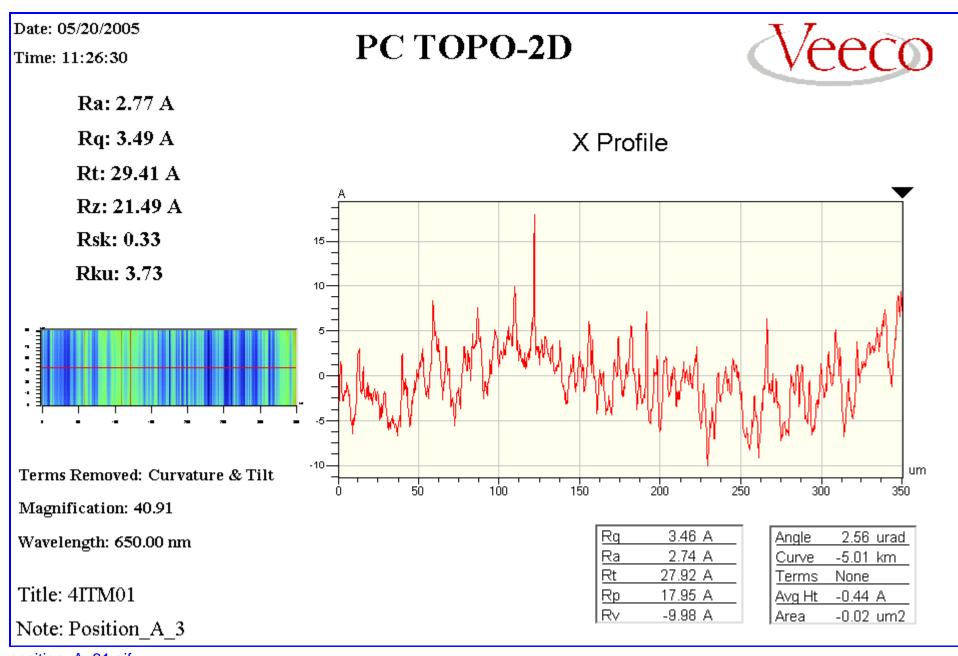
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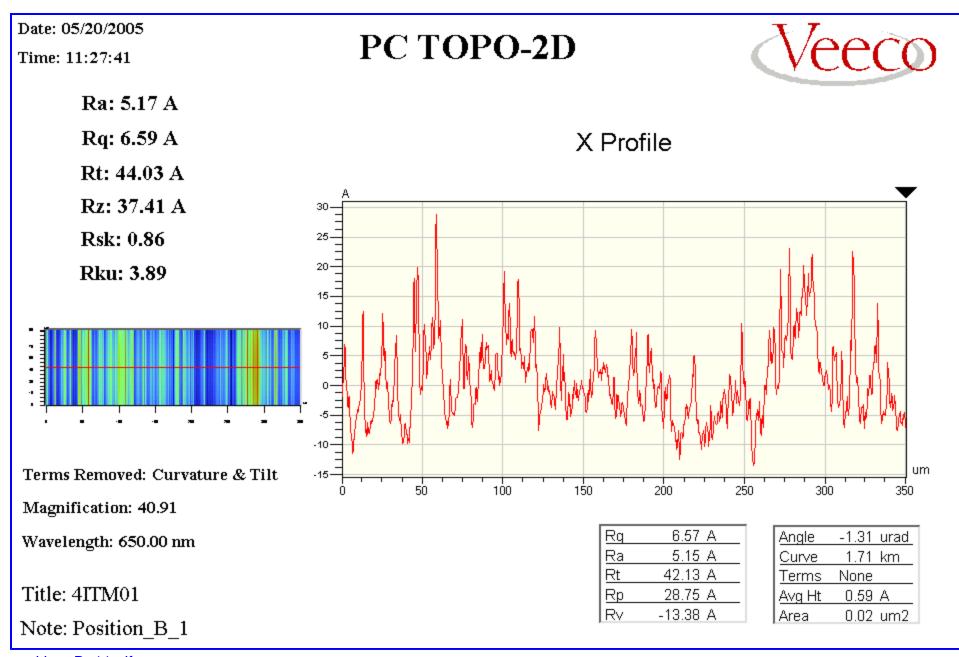
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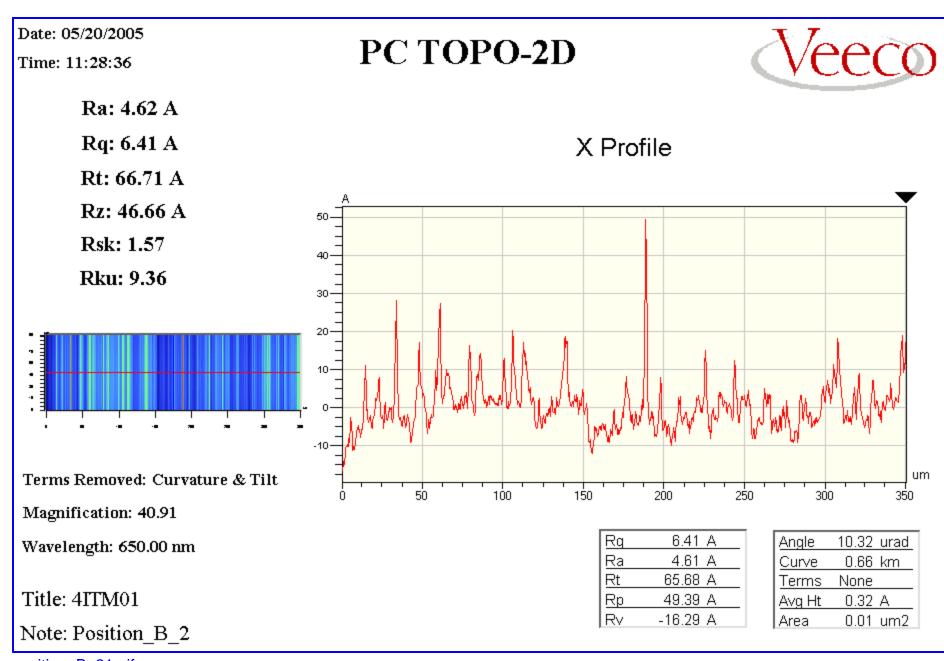
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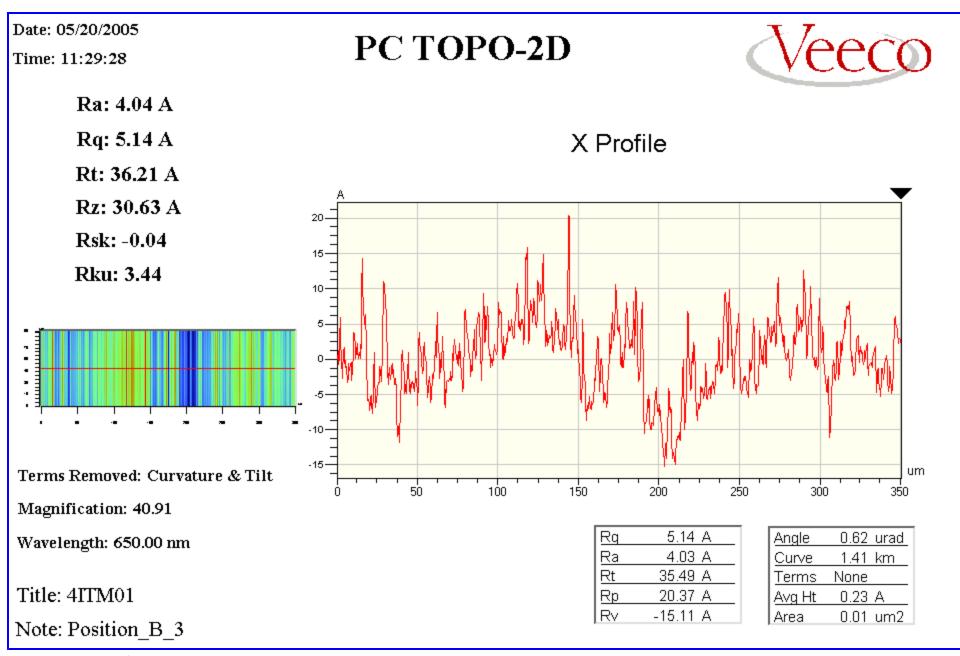
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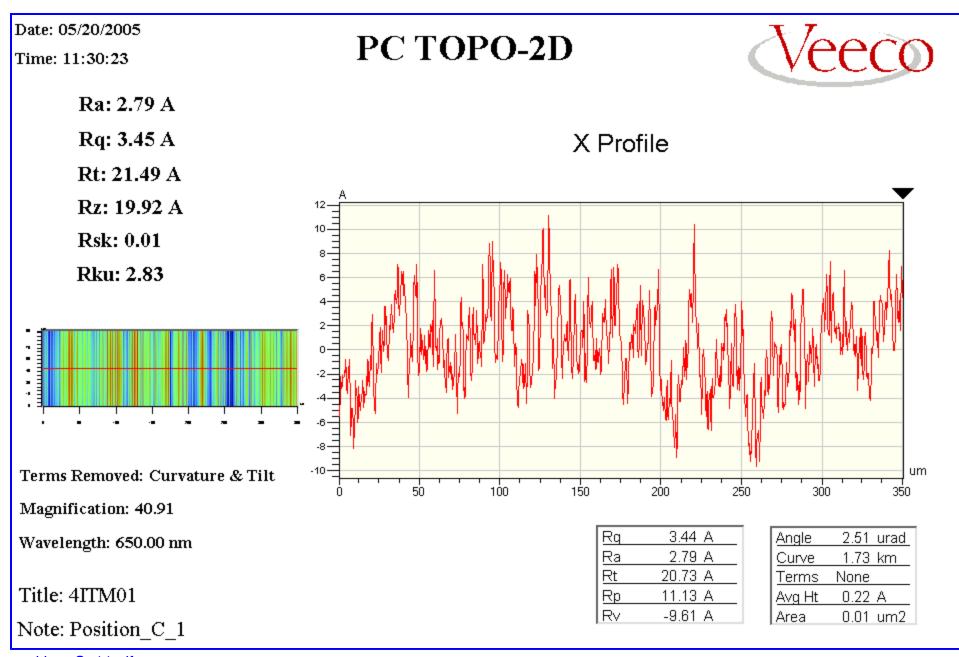
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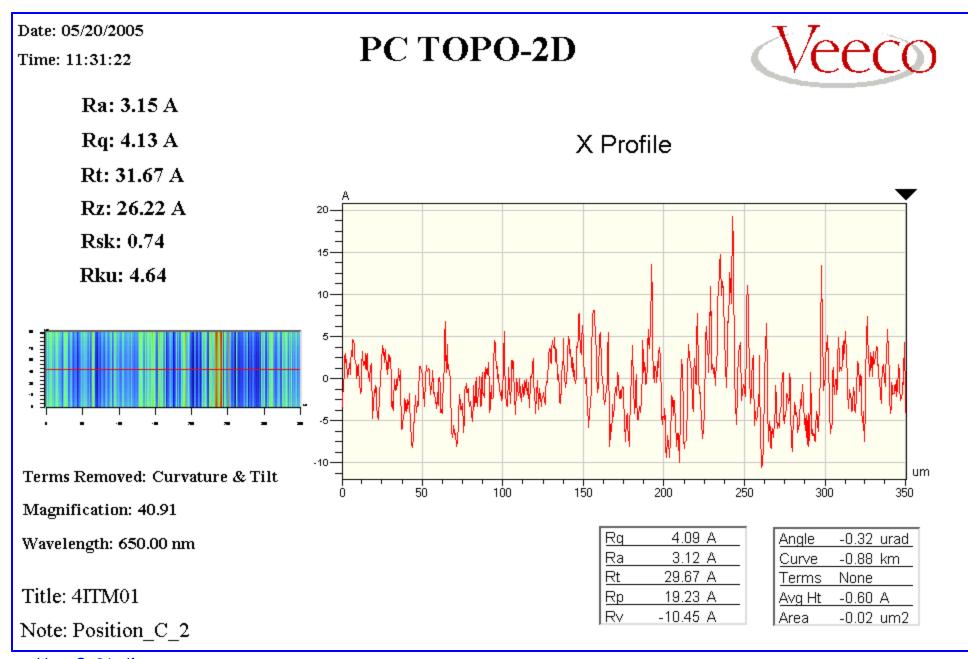
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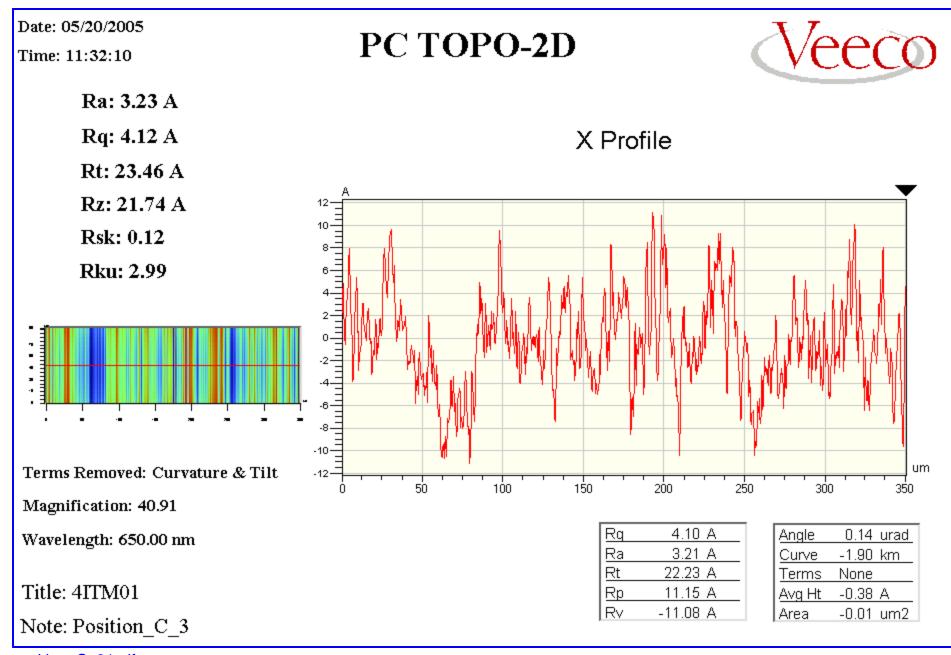
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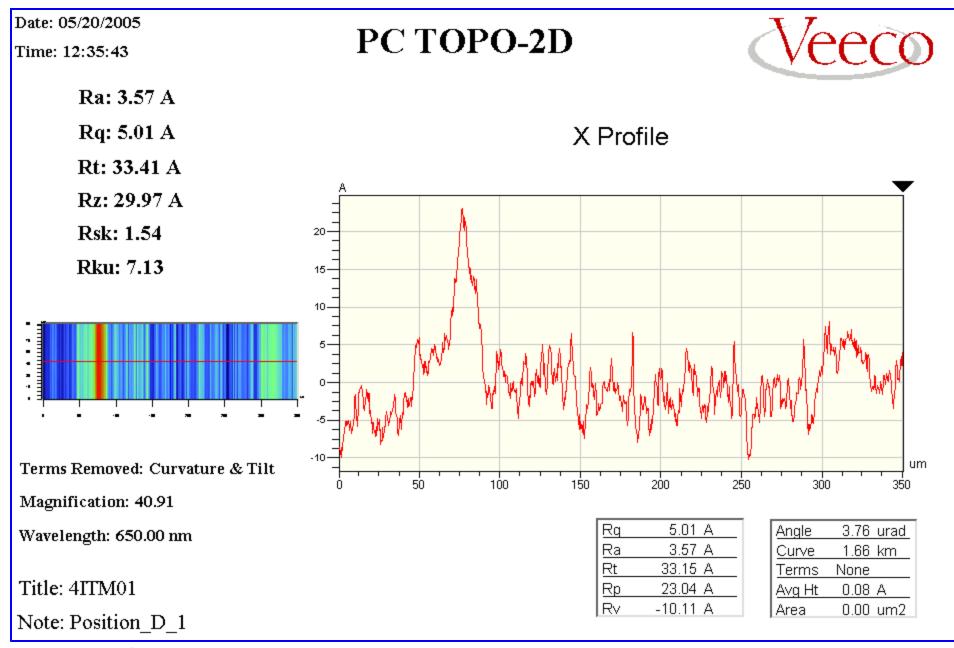
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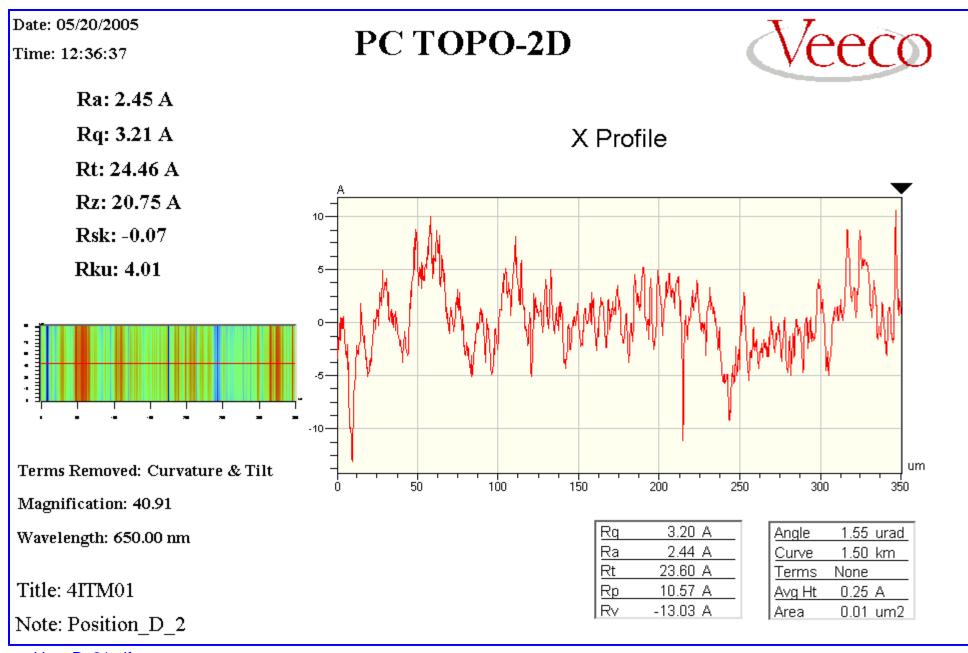
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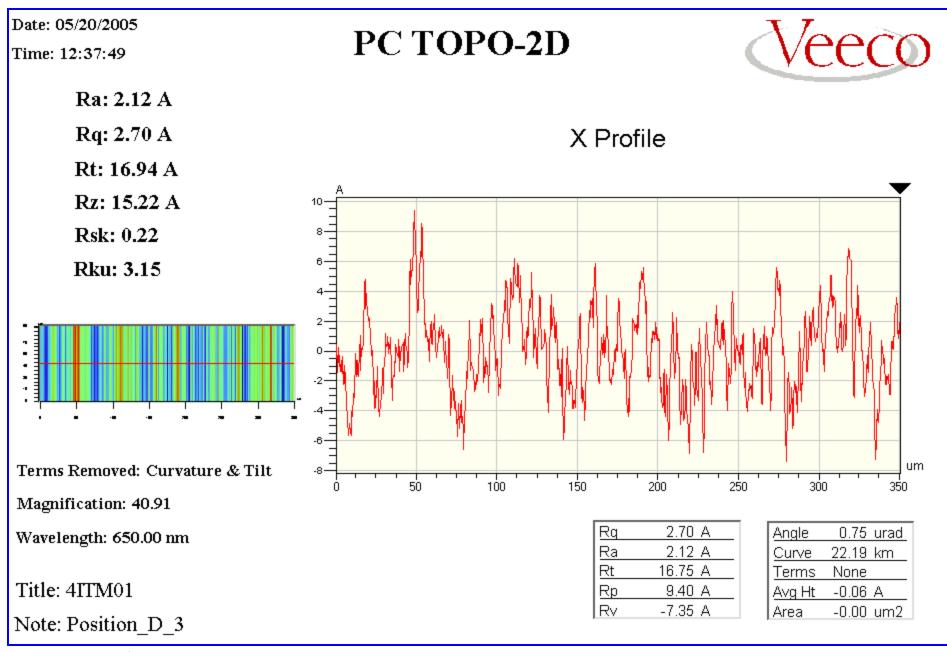
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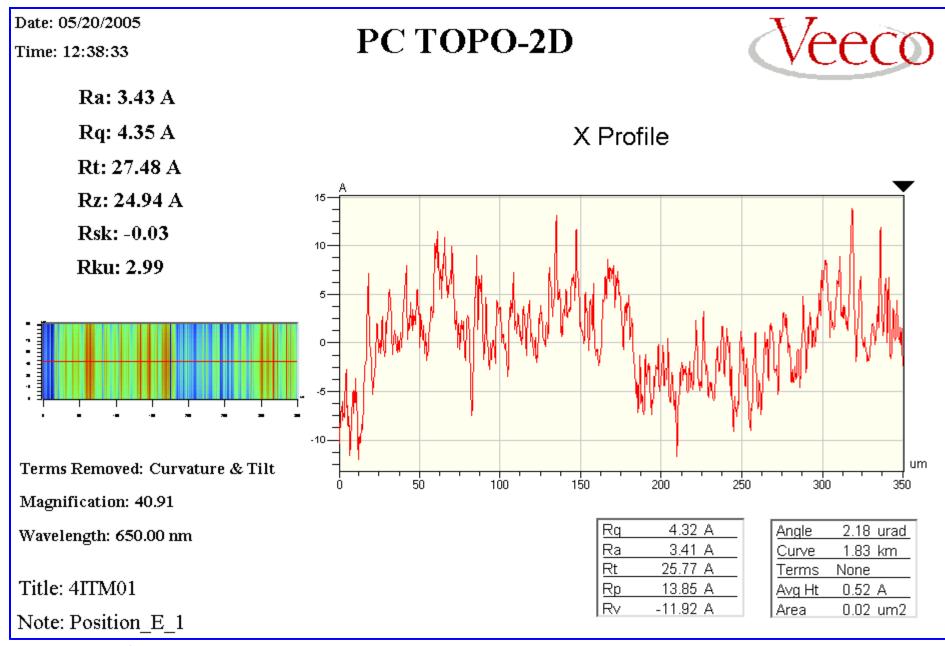
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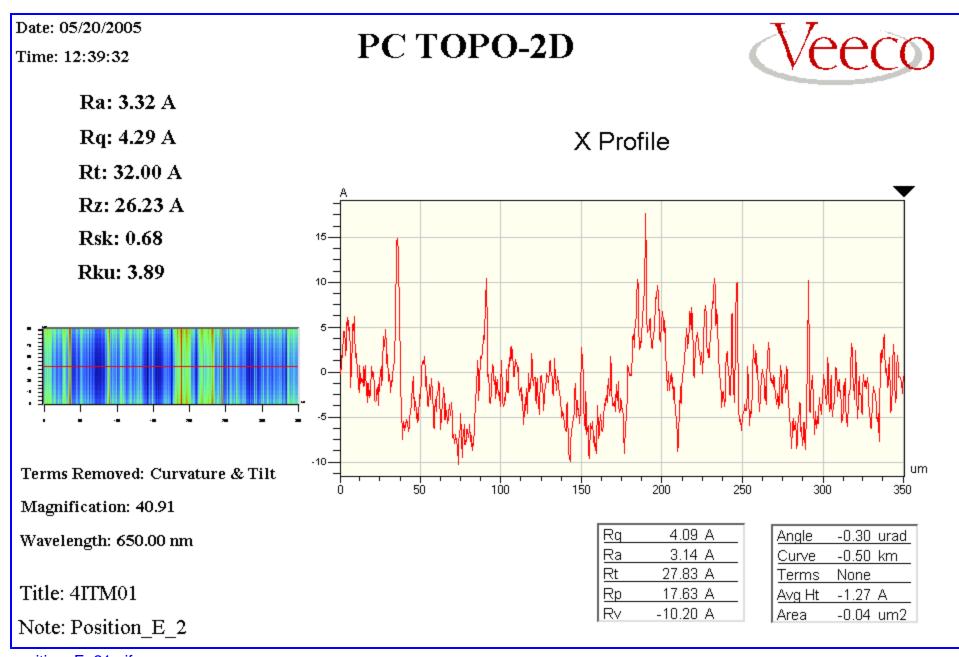
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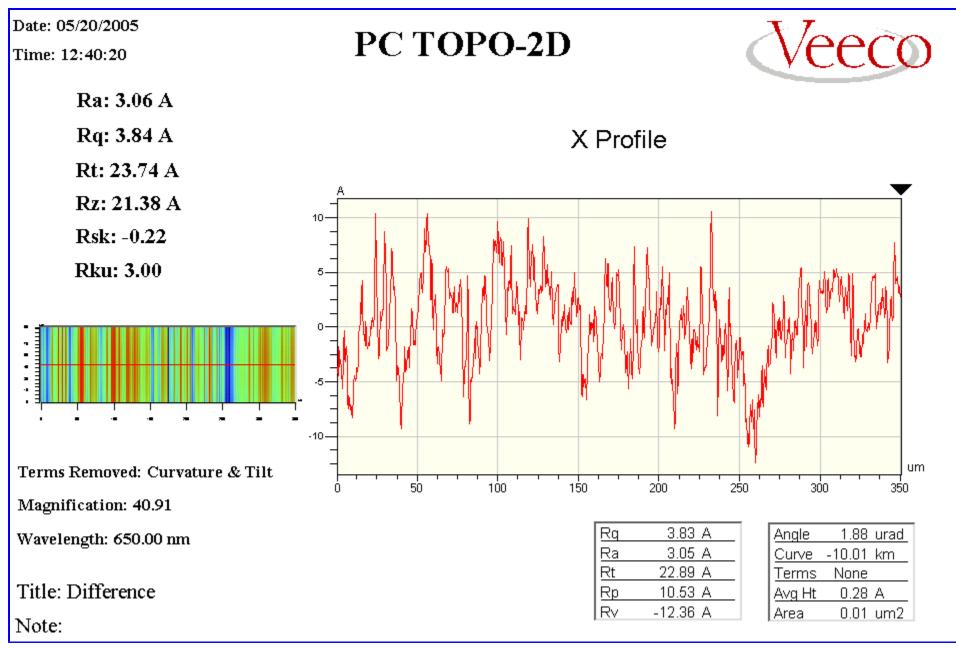
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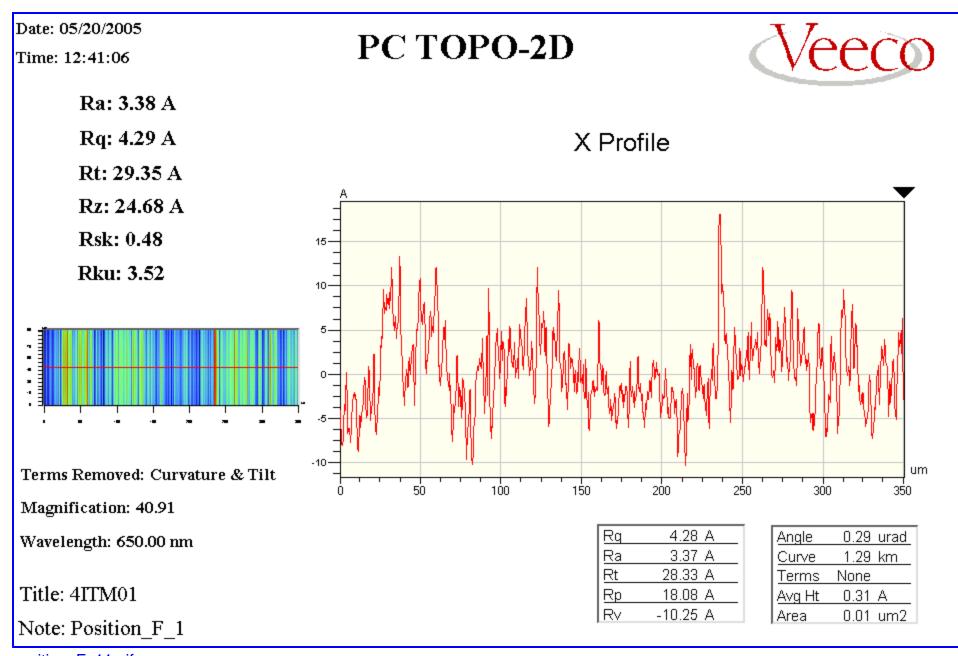
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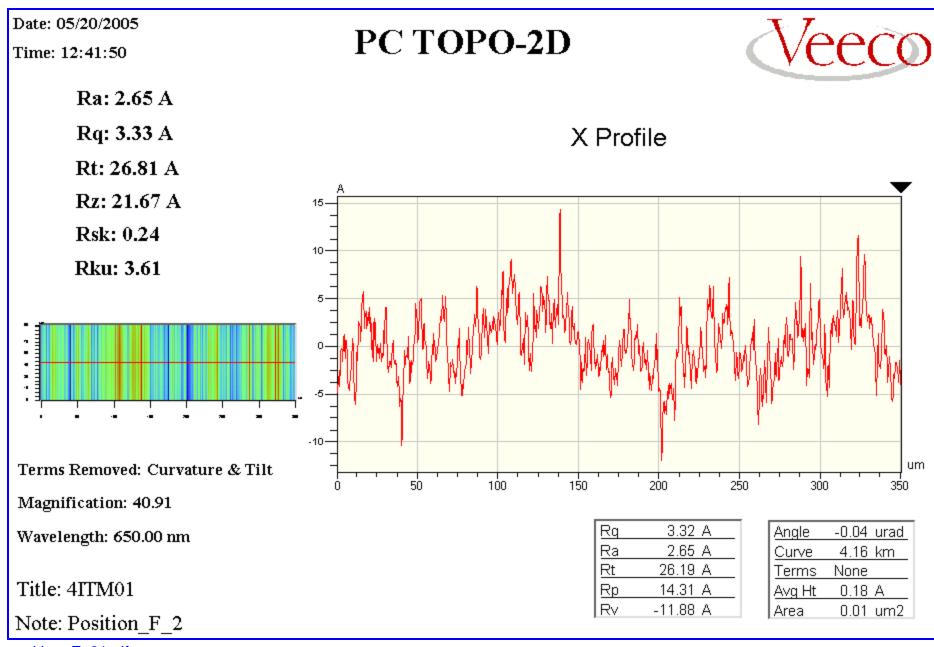
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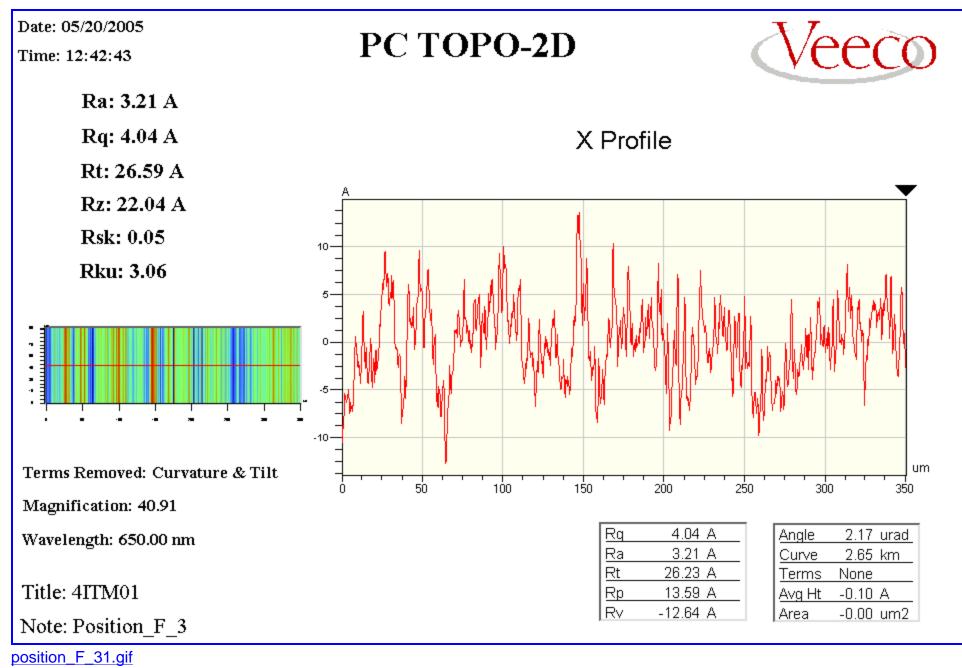
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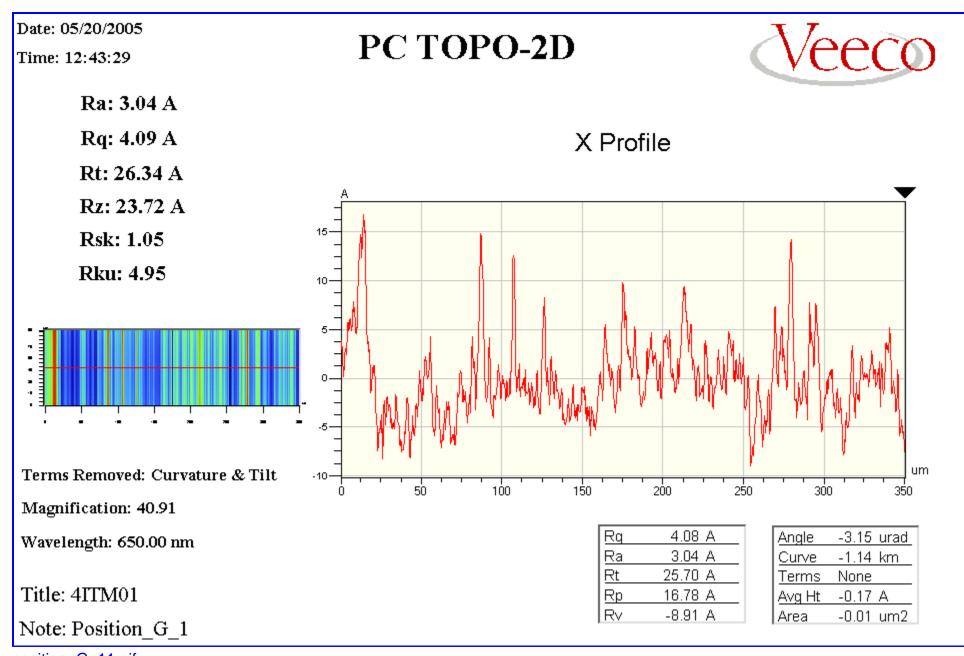


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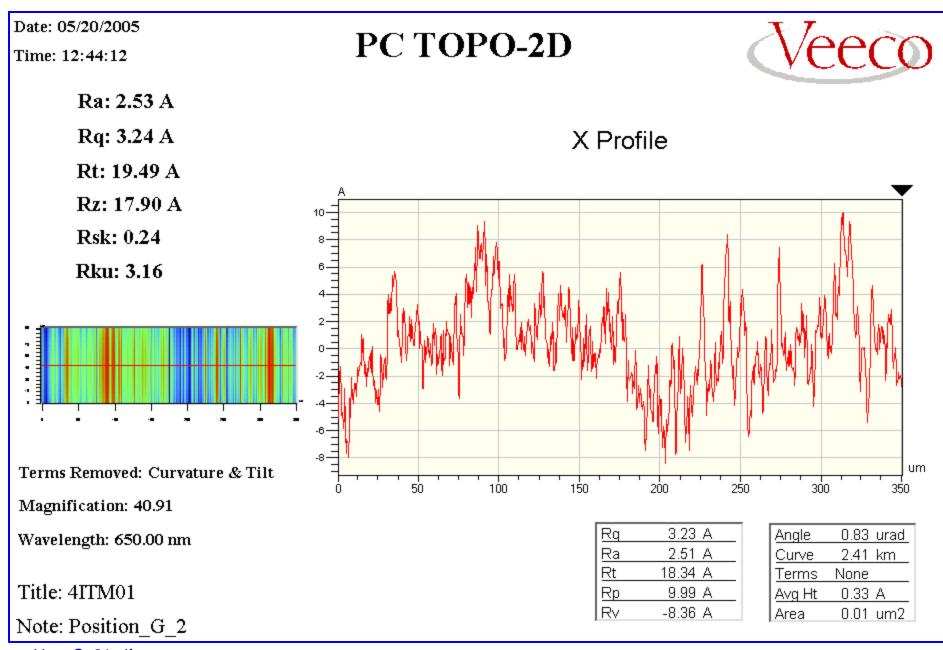


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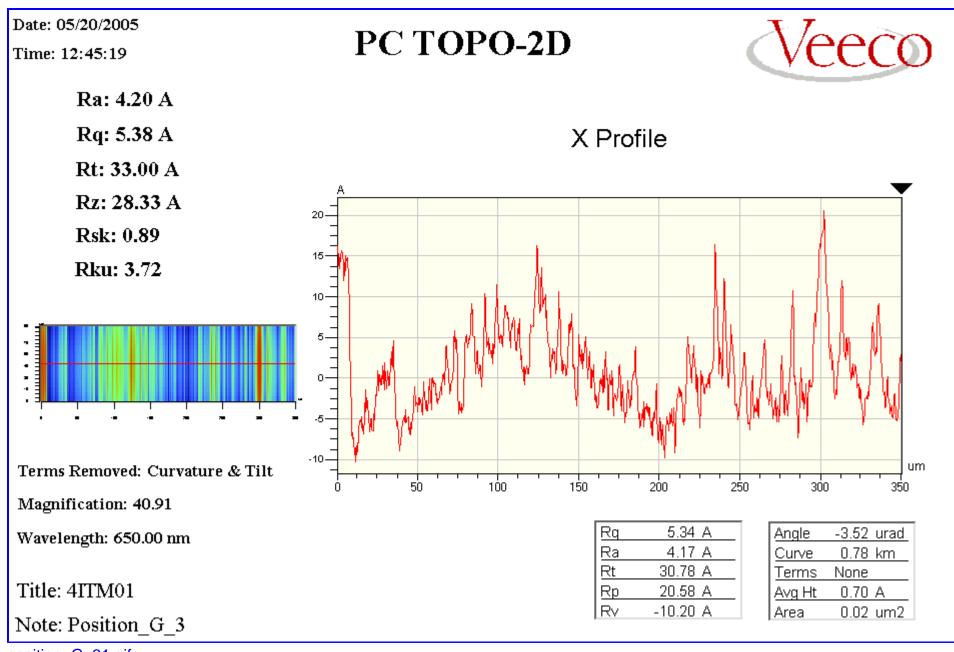




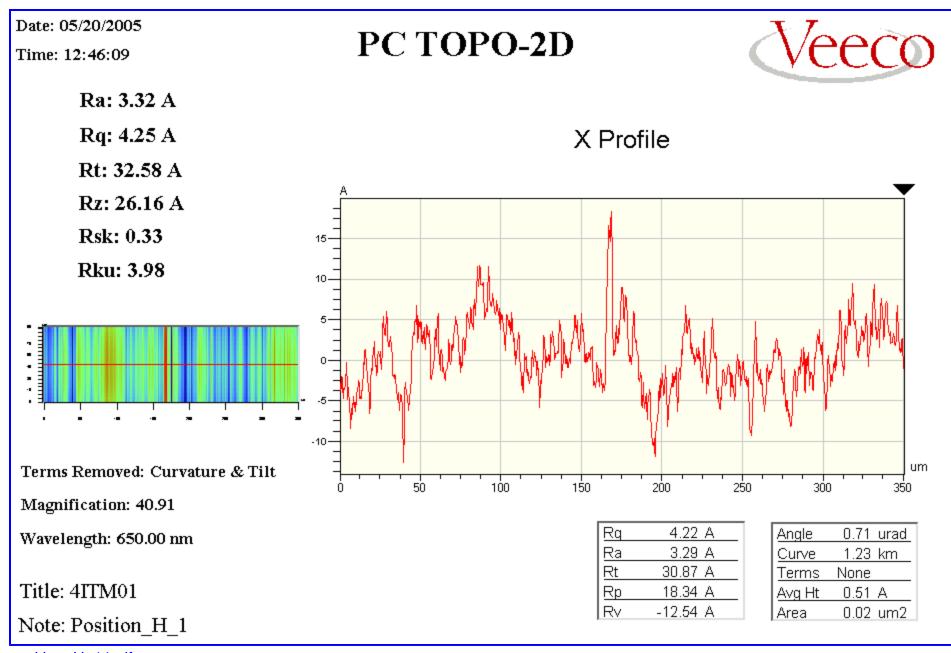
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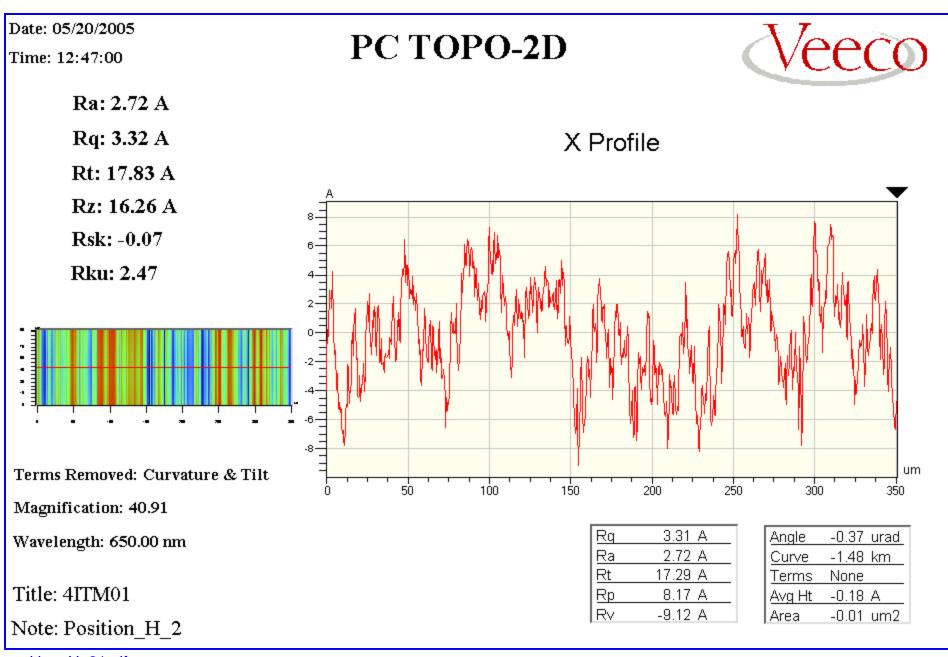
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position_G_31.gif



position_H_11.gif



position_H_21.gif